

DP838671R

Compliance Test Results

2020/4/13

Contents of Compliance Test:

- Conduct all test items of 10Base-Te, 100Base-TX and 1000Base-T
 - But Harmonic Contents of 10Base-T was not conducted, since the external measuring instrument could not output the ALL1 signal.

- Number of Test Board:

- No3, No4

| | | | |
|--------------|---|-------------------|---|
| • 10Base-Te | : | Board No3 | Conducted all test items at only Port1 |
| • 100Base-TX | : | Board No3 | Conducted all test items with all Ports |
| • 1000Base-T | : | Board No3 and No4 | Conducted all test items with all Ports |

Compliance Test Results at 2020/4/13:

| | |
|------------|--------------------|
| 10Base-Te | : 4 fail items |
| 100Base-TX | : Passed all items |
| 1000Base-T | : 1 fail item |

Compliance Test Results of 10Base-T/10Base-Te:

2020.4.13

| 測定時間 30分~1時間30分程度 | | | | | 1回目 (3/11) | | 2回目 (4/13~15) | | |
|---|----|---------|-----|--|--------------|------------|---------------|-----|--|
| 1回目: 10BASE-T 2回目: 10BASE-Te | | | | Load1: 115Ωと180μHの並列 Load2: 76.8Ωと220μHの並列 Load3: 100Ω | 試験結果 (Port1) | | 試験結果 (Port1) | | コメント) NG項目について、書き加減(全然だめ、惜しいなど)を記載してください。可能であれば数値で表現 |
| 試験項目 | 点数 | テストパターン | TPM | 負荷 | No8 | No3 | No3 | No4 | |
| Link Test Pulse, with TPM | 1 | リンクパルス | あり | Load1/Load2/Load3 | OK | | OK | --- | |
| Link Test Pulse, without TPM | 1 | リンクパルス | なし | Load1/Load2/Load3 | OK | | OK | --- | |
| TP_IDL Template, with TPM (last bit CD0) | 1 | 疑似ランダム | あり | Load1/Load2/Load3 | NG (Load2) | NG (Load2) | NG(Load2) | --- | NGの程度: 中 Load2の試験において、電圧が低くマスクに当たる |
| TP_IDL Template, with TPM (last bit CD1) | | 疑似ランダム | あり | Load1/Load2/Load3 | NG (Load2) | NG (Load2) | NG(Load2) | --- | 上に同じ |
| MAU Template | | 疑似ランダム | あり | Load3 | NG | NG | OK | --- | |
| Jitter with TPM | | 疑似ランダム | あり | Load3 | OK | | OK | --- | |
| TP_IDL Template, without TPM (last bit CD0) | 1 | 疑似ランダム | なし | Load1/Load2/Load3 | NG (Load1) | NG (Load3) | OK | --- | NGの程度: 中 波形立ち上がり部分で時間軸方向のジッタがあり、マスクに当たる |
| TP_IDL Template, without TPM (last bit CD1) | | 疑似ランダム | なし | Load1/Load2/Load3 | NG (Load1) | NG (Load1) | NG(Load1) | --- | |
| Jitter without TPM | | 疑似ランダム | なし | Load3 | OK | | OK | --- | |
| Peak Differential Voltage | | 疑似ランダム | なし | Load3 | NG | NG | OK | --- | |
| Harmonic Content | 1 | ALL1 | なし | Load3 | 未 | | 実施無し | --- | |
| Common Mode Output Voltage | 1 | 疑似ランダム | なし | 47.5Ω×2 | OK | | OK | --- | |
| Transmitter Return Loss | 1 | 疑似ランダム | なし | Zc=85/100/111Ω | NG(111Ω) | NG(111Ω) | NG | --- | NGの程度: 中 111ΩでのLossが大きい(前回と同様?) |
| Receiver Return Loss | 1 | 疑似ランダム | なし | Zc=85/100/111Ω | OK | | OK | --- | |

Compliance Test Results of 100Base-TX:

| 測定時間 30分程度 | | | | | 1回目 (3/11) | | 2回目 (4/13~15) | | | | | |
|---------------------------------------|----|-------------|-----|-------------|--------------|-----|---------------|----------------|-------|----|-----|--|
| 100BASE-TX | | | | | 試験結果 (Port1) | | 試験結果 (Port 全) | | | | | |
| 試験項目 | 点数 | テストパターン | TPM | 負荷 | No8 | No3 | No3 | No4 | コメント) | | | |
| UTP +Vout Differential Output Voltage | 1 | Test Mode 5 | なし | Load3(100Ω) | OK | | OK | --- | | | | |
| UTP -Vout Differential Output Voltage | | | | | NG | OK | OK | --- | | | | |
| UTP Signal Amplitude Symmetry | | | | | OK | | OK | --- | | | | |
| +Vout Overshoot | | | | | OK | | OK | --- | | | | |
| -Vout Overshoot | | | | | OK | | OK | --- | | | | |
| UTP AOI Template | | | | | OK | | OK | --- | | | | |
| AOI +Vout Rise Time | | | | | OK | | OK | --- | | | | |
| AOI +Vout Fall Time | | | | | OK | | OK | --- | | | | |
| AOI +Vout Rise/Fall Symmetry | | | | | OK | | OK | --- | | | | |
| AOI -Vout Rise Time | | | | | OK | | OK | --- | | | | |
| AOI -Vout Fall Time | | | | | OK | | OK | --- | | | | |
| AOI -Vout Rise/Fall Symmetry | | | | | OK | | OK | --- | | | | |
| AOI Overall Rise/Fall Symmetry | | | | | OK | | OK | --- | | | | |
| Transmit Jitter | | | | | OK | | OK | --- | | | | |
| Duty Cycle Distortion | | | | | OK | | OK | --- | | | | |
| Transmitter Return Loss | | | | | 1 | | | Zs=85/100/115Ω | OK | OK | --- | |
| Receiver Return Loss | | | | | 1 | | | Zs=85/100/115Ω | OK | OK | --- | |
| 計3点 | | | | | | | | | | | | |

Compliance Test Results of 1000Base-T:

| 測定時間 1時間~1時間30分程度 | | | | | 1回目 (3/11) | | 2回目 (4/13) | | |
|--|----|------------|-----|----------------|--------------|-------------|---|--|---|
| 1000BASE-T | | | | | 試験結果 (Port1) | | 試験結果 (Port 全) | | |
| 試験項目 | 点数 | テストパターン | TPM | 負荷 | No8 | No3 | No3 | No4 | コメント) |
| Point A Peak Output Voltage(w/ Disturbing Signal) | 1 | Test Mode1 | なし | | NG(A,B,C,D) | NG(A,B,C,D) | OK | OK | Resolved by adding register setting |
| Point B Peak Output Voltage(w/ Disturbing Signal) | | | | | NG(A,B,C,D) | NG(A,B,C,D) | OK | OK | |
| Difference A,B Peak Output Voltage(w/ Disturbing Signal) | | | | | NG(A,B,C,D) | NG (A,D) | Port1 : NG (≠A,A,D) Port2 : NG (≠A,A,B) Port3 : NG (≠A,A,B) Port4 : NG (≠A,A,C,D) TEST : OK | Port1 : NG (≠A,D) Port2 : NG (≠A,A,D) Port3 : NG (≠A,D) Port4 : NG (≠A,A,B,C,D) TEST : NG (≠A,B,C,D) | NGの程度 : 中 Point A,B間の電圧の誤差が大きい (1%未満のところ1.3~2%程度) |
| Point C Peak Output Voltage(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point D Peak Output Voltage(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point A Template Test(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point B Template Test(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point C Template Test(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point D Template Test(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point F Template Test(w/ Disturbing Signal) | | | | | OK | OK | OK | OK | |
| Point H Template Test(w/ Disturbing Signal) | OK | OK | OK | OK | | | | | |
| Point G Droop Test(w/ Disturbing Signal) | OK | OK | OK | OK | | | | | |
| Point J Droop Test(w/ Disturbing Signal) | OK | OK | OK | OK | | | | | |
| Transmitter Distortion(w/ Disturbing Signal) | 1 | Test Mode4 | | | NG(A,C) | NG (C) | OK | OK | The countermeasure was effective (it was assumed that channel interference and only the channel concerned was output) |
| MDI Common Mode Output Voltage | 1 | Test Mode4 | | | OK | | OK | OK | |
| MASTER mode JTxOut | 1 | Test Mode2 | | | OK | | OK | OK | |
| Jitter MASTER Filtered (w/o TX_TCLK) | | | OK | | OK | OK | | | |
| Jitter MASTER Unfiltered (w/o TX_TCLK) | | | OK | | OK | OK | | | |
| SLAVE mode JTxOut | 1 | Test Mode2 | | | OK | | OK | OK | |
| Jitter SLAVE Filtered (w/o TX_TCLK) | | | OK | | OK | OK | | | |
| Jitter SLAVE Unfiltered (w/o TX_TCLK) | | | OK | | OK | OK | | | |
| MDI Return Loss | 1 | Test Mode4 | | Zs=85/100/115Ω | OK | | OK | OK | |

計6点

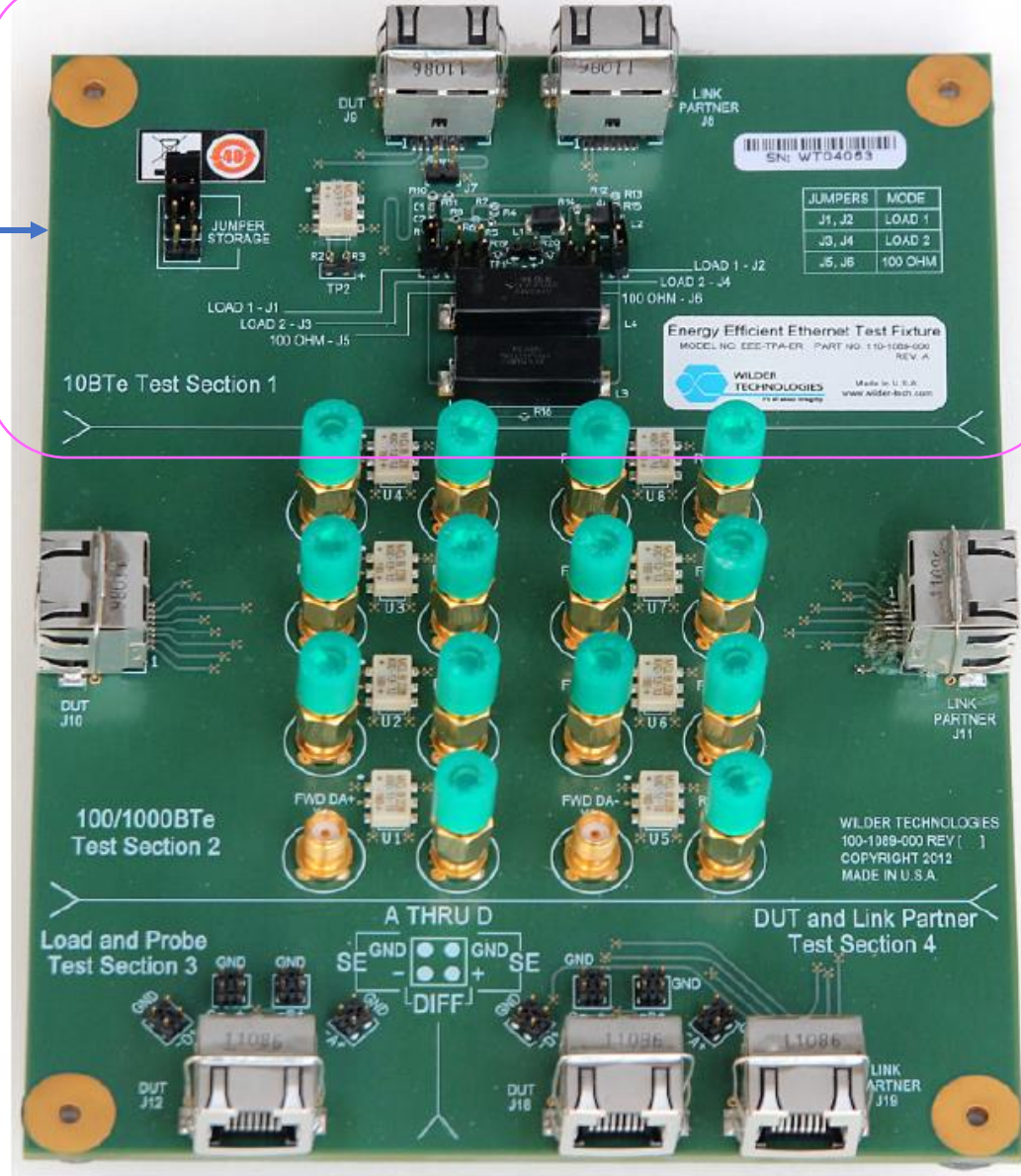
※1000BASE-Tは4ペア (A,B,C,D)で実施

Measuring instruments:

| Device Description | | | |
|-------------------------|----------------------------------|--------------|---|
| | 10Base-Te | 100Base-TX | 1000Base-T |
| ReturnLossTest | Use Vector Network Analyzer | Same as left | Same as left |
| DisturberSource | Useb Agilent 33250A | Same as left | Same as left |
| Test Session Details | | | |
| Infiniium SW Version | 06.00.00628 | 04.60.0011 | Same as left |
| Infiniium Model Number | DSAV204A | DSO9404A | Same as left |
| Infiniium Serial Number | MY56110125 | MY53450126 | Same as left |
| Application SW Version | 2.44 | 2.21 | Same as left |
| Probe | Model : 1131A Head : E2678A/B | Same as left | Model : User Deffined Head : User Deffined |
| | | | |

Test fixture (10Base-Te with TPM):

10Base-Te

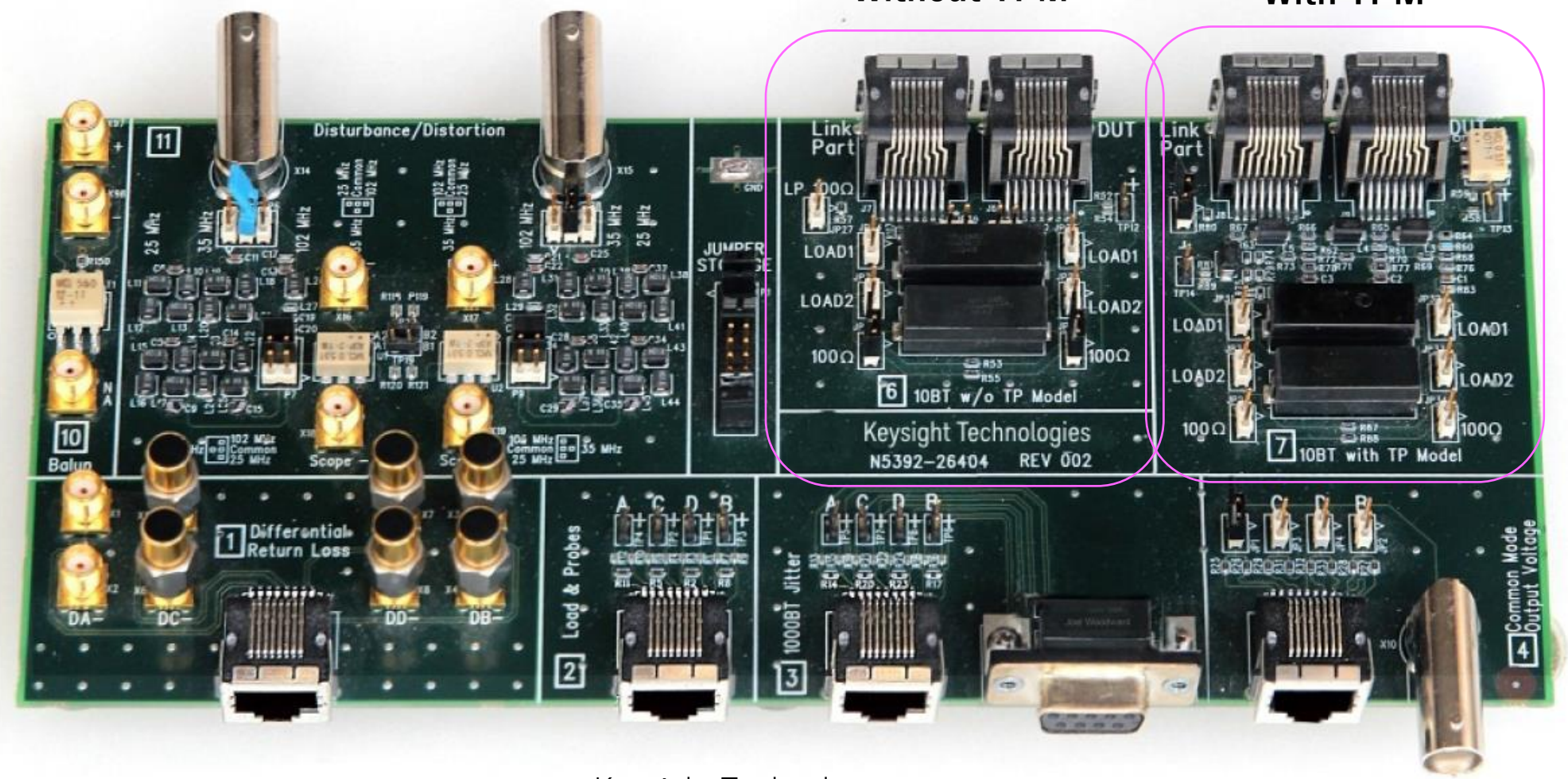


Wilder Technologies
Model Name: 110-1089-000

Test fixture (10Base-Te without TPM):

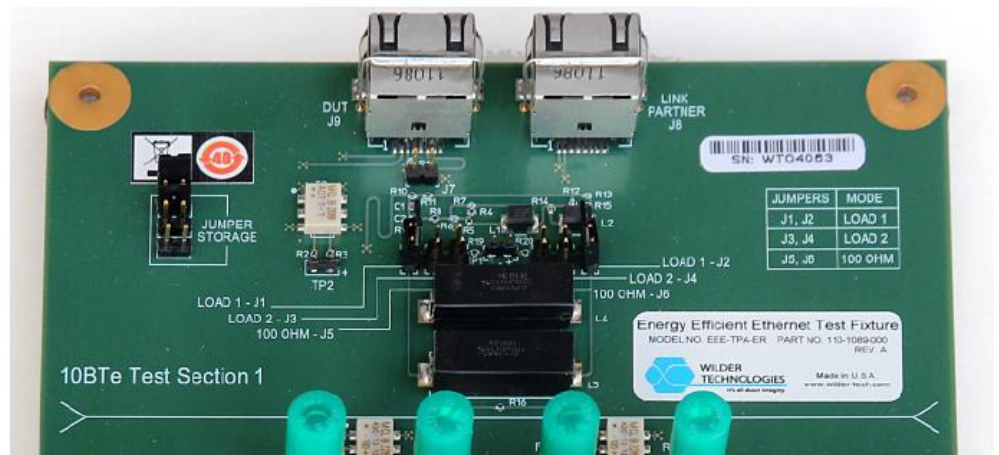
Section 6
10Base-Te/10Base-T
Without TPM

Section 7
10Base-T
With TPM

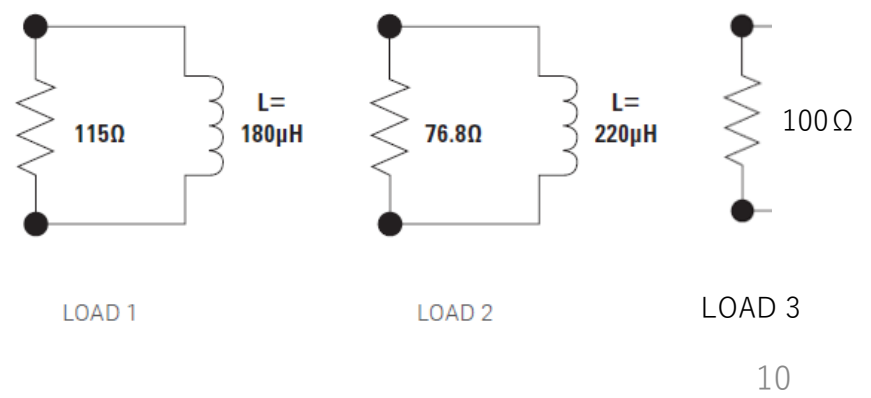
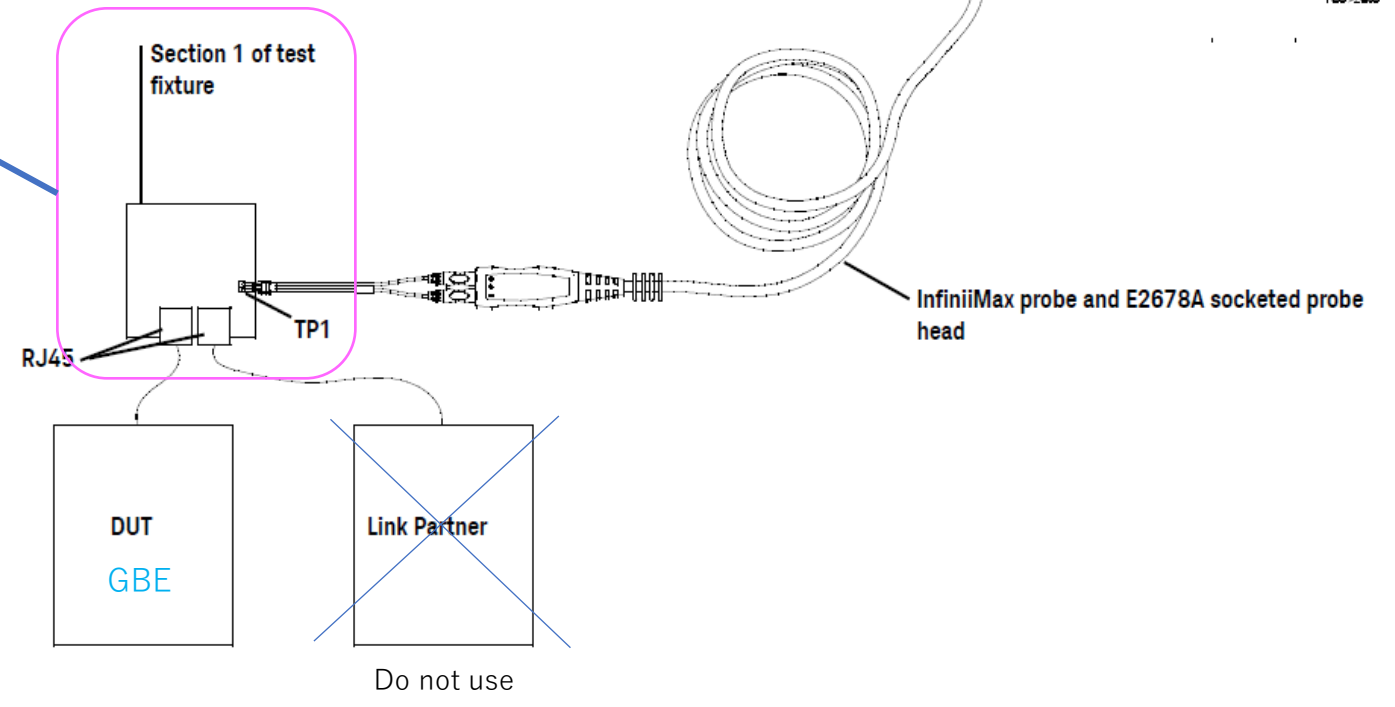
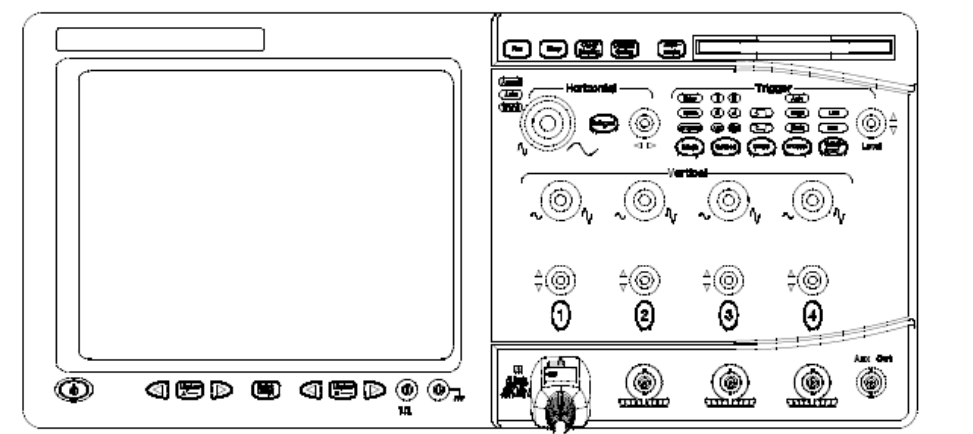


Keysight Technology
Model Name: N5395C

Measurement system (10Base-Te with TPM):



TEST FIXTURE (Section 1)
 Wilder Technologies
 Model Name: 110-1089-000



Measurement system (10Base-Te with TPM):

MDI Mode:
 DATA A: DUT send
 DATA B: DUT receive

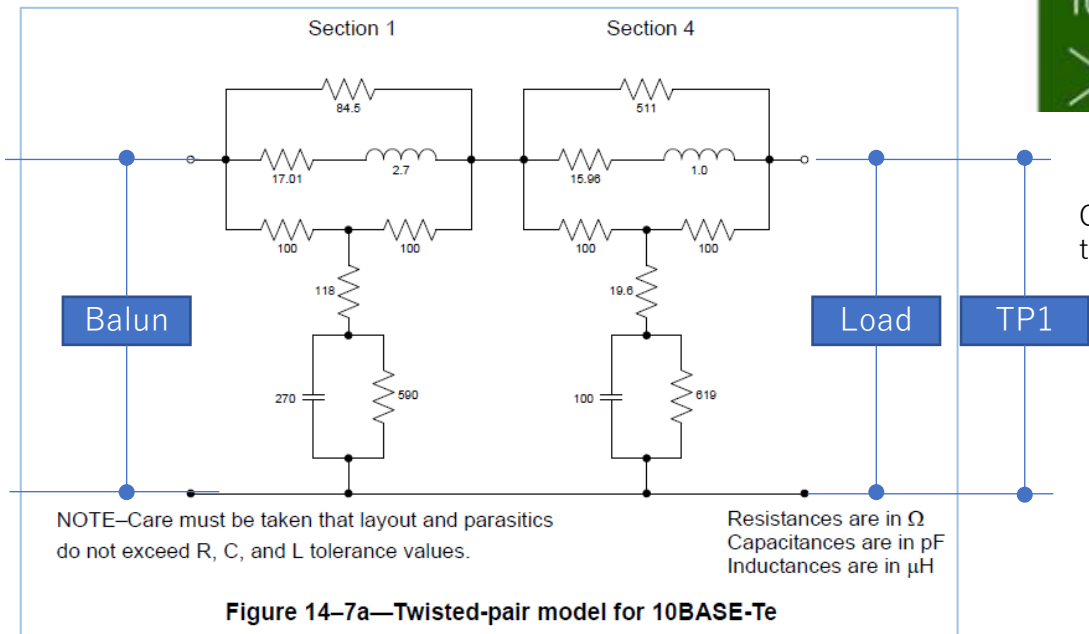
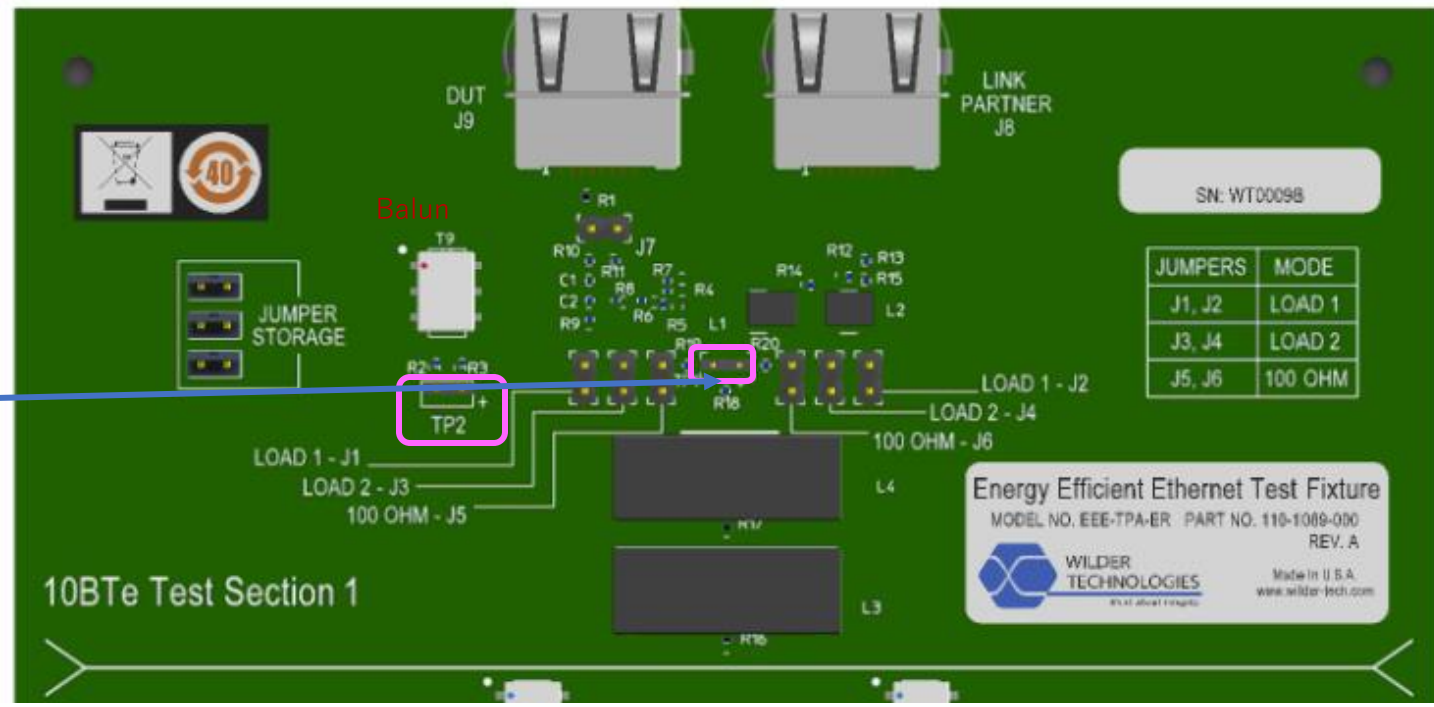
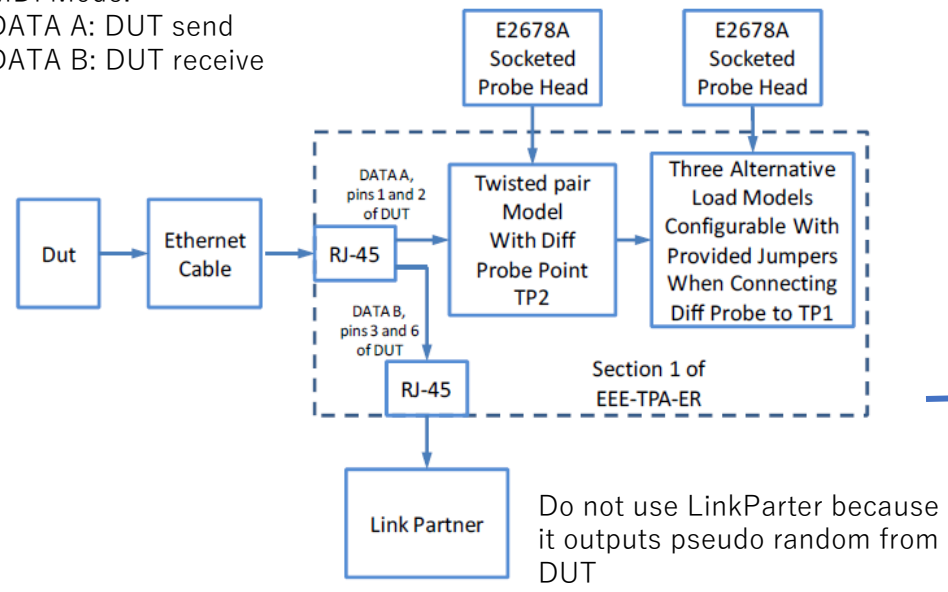
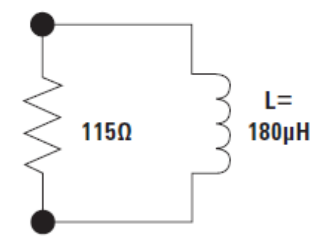
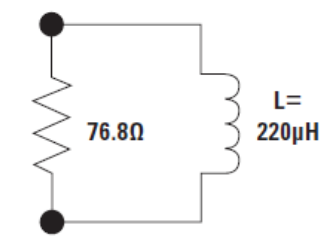


Figure 14-7a—Twisted-pair model for 10BASE-Te

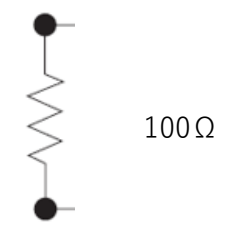
Connect to Probe



LOAD 1

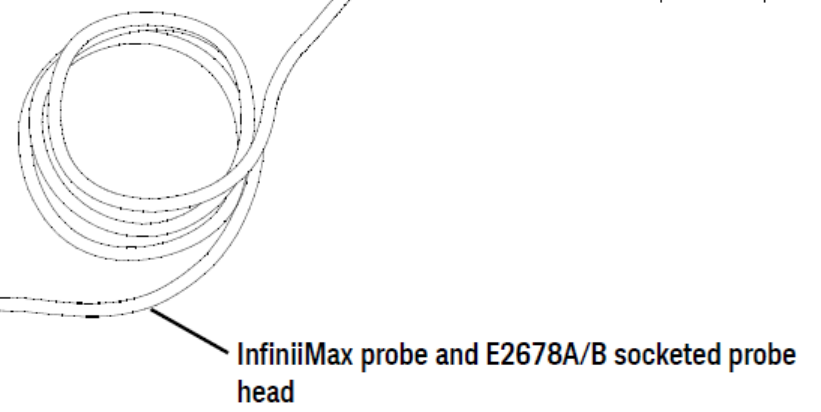
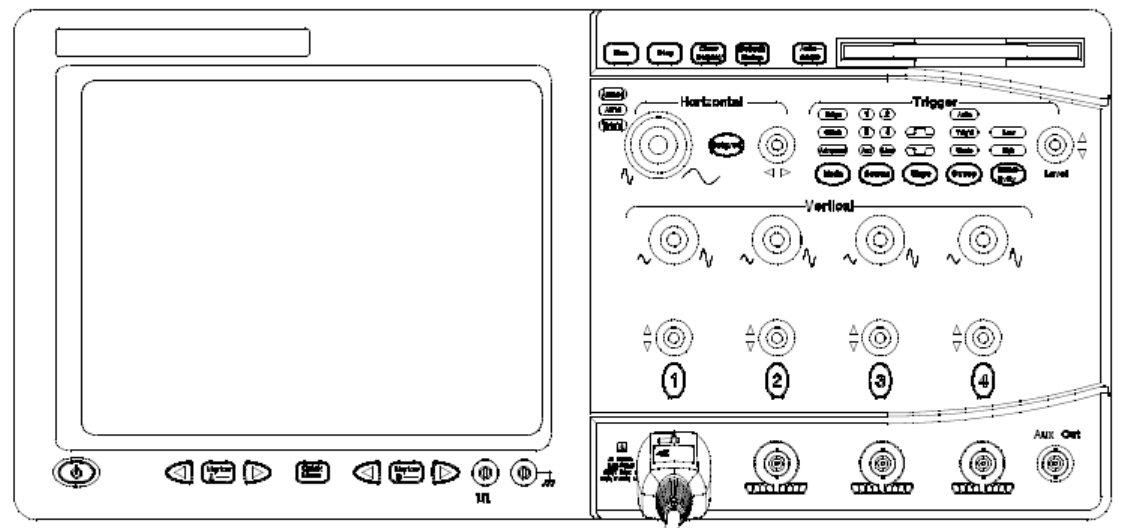
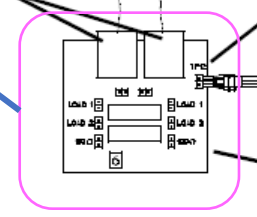
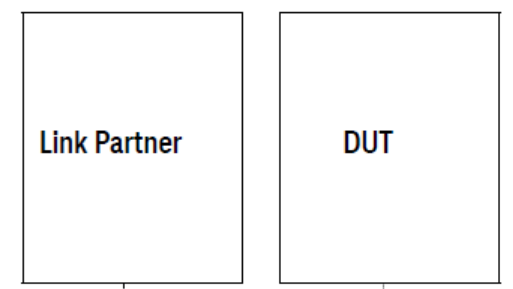
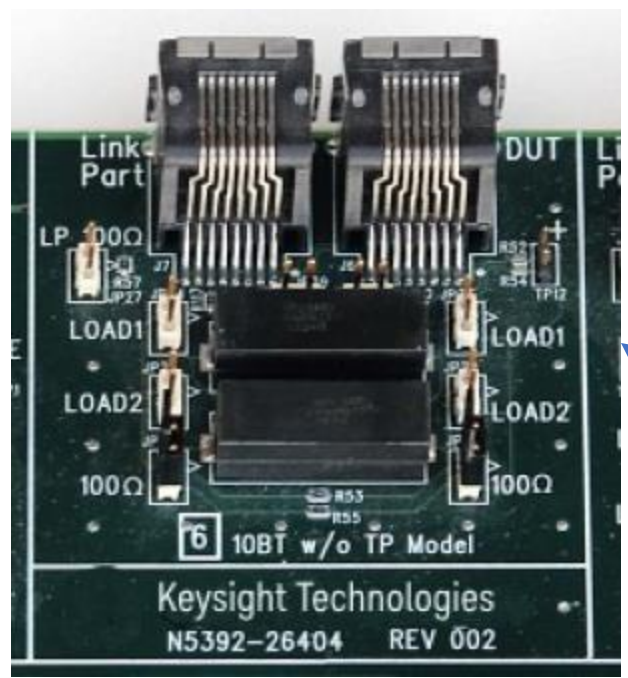


LOAD 2



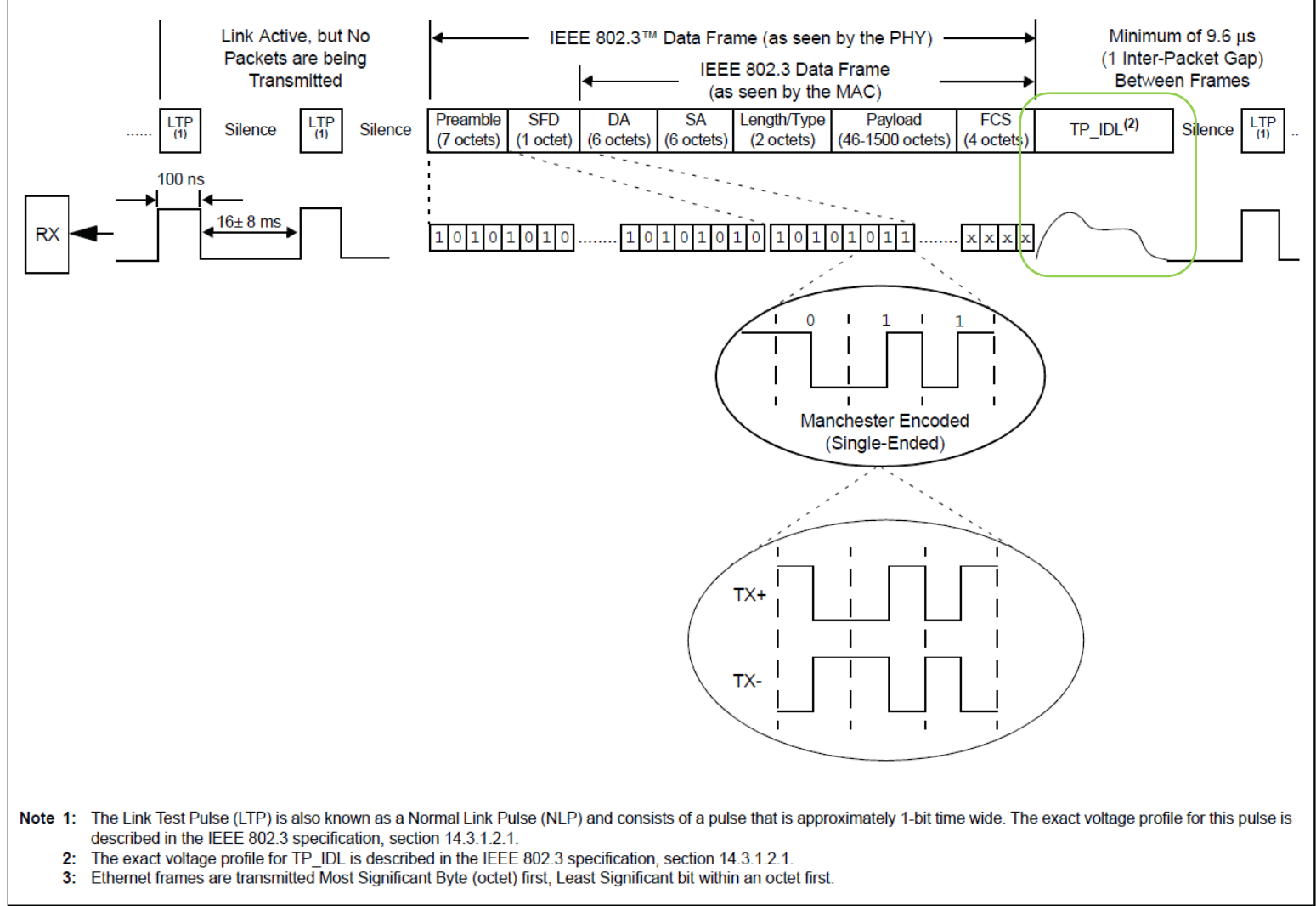
LOAD 3

Measurement system (10Base-Te without TPM):

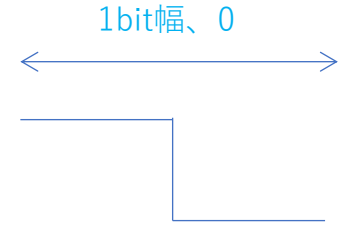


10Base-Te ~TP_IDL Template, with TPM (last bit CD0/1)~ - About TP_IDL signal

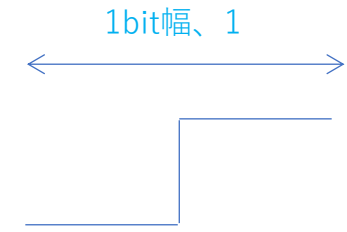
FIGURE 12: 10 Mb/s ETHERNET STREAM⁽³⁾



CD0/1 = Clock xor Data



CD0 : Clock Data Zero



CD1 : Clock Data One

10Base-Te ~TP_IDL Template, with TPM (last bit CD0/1)~ - About pulse mask

The same mask applied with / without TPM and Load1 / 2 / 3

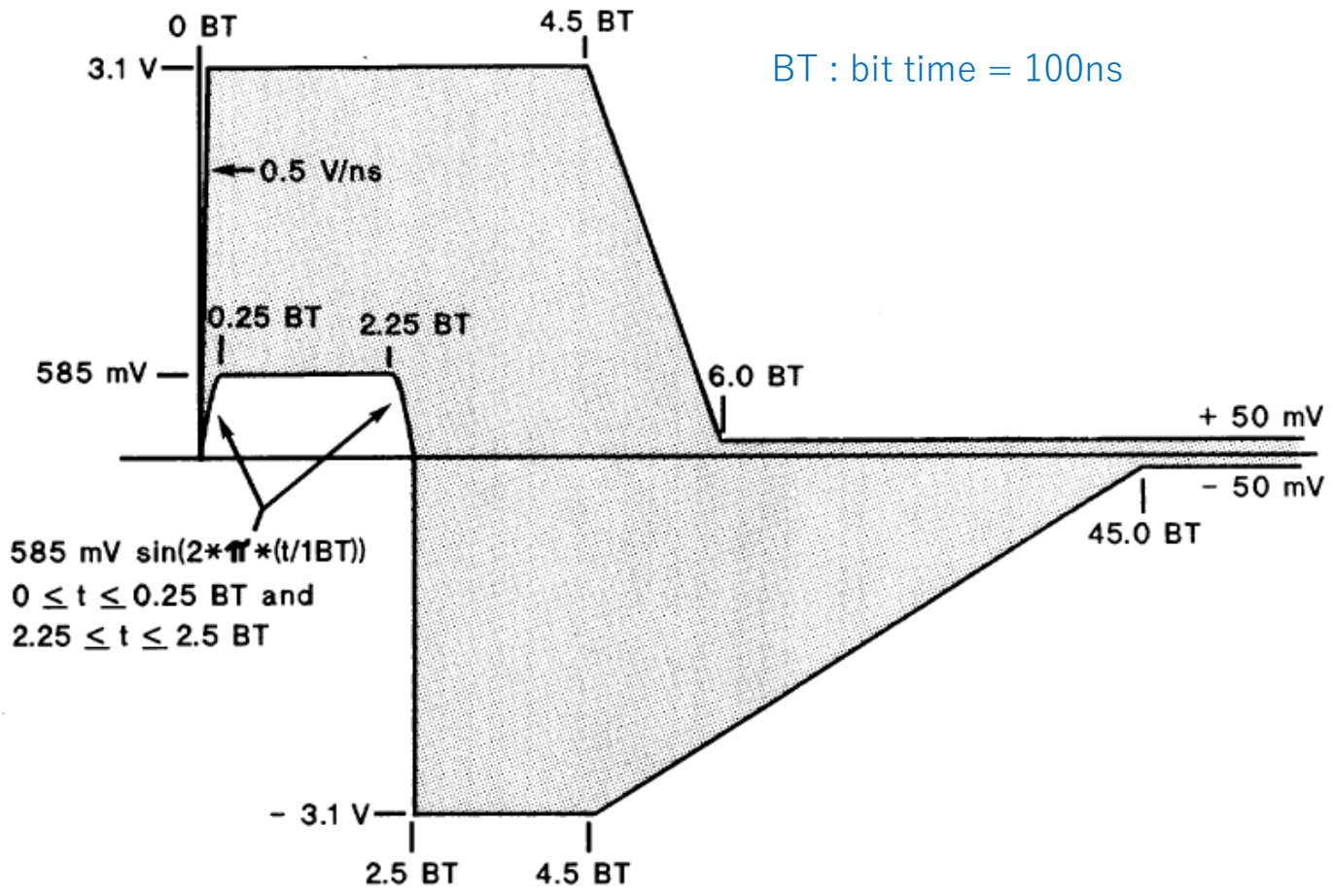
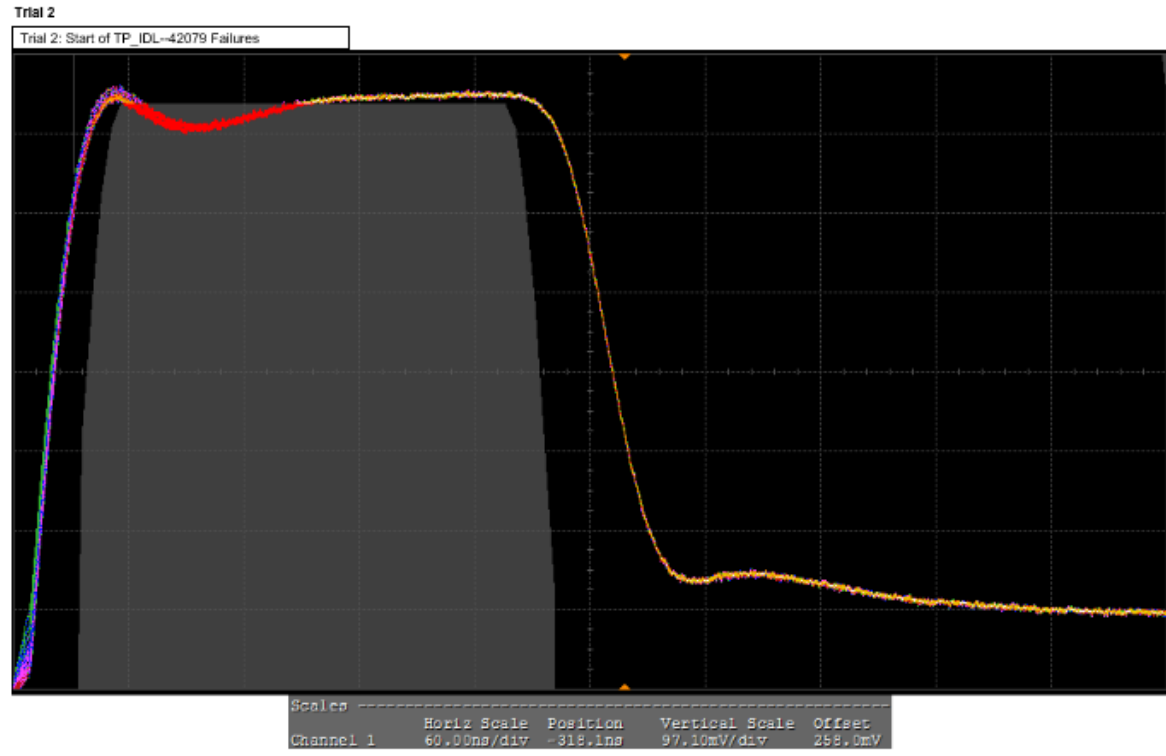


Figure 14-11—Transmitter waveform for start of TP_IDL
IEEE std 802.3 - 2018

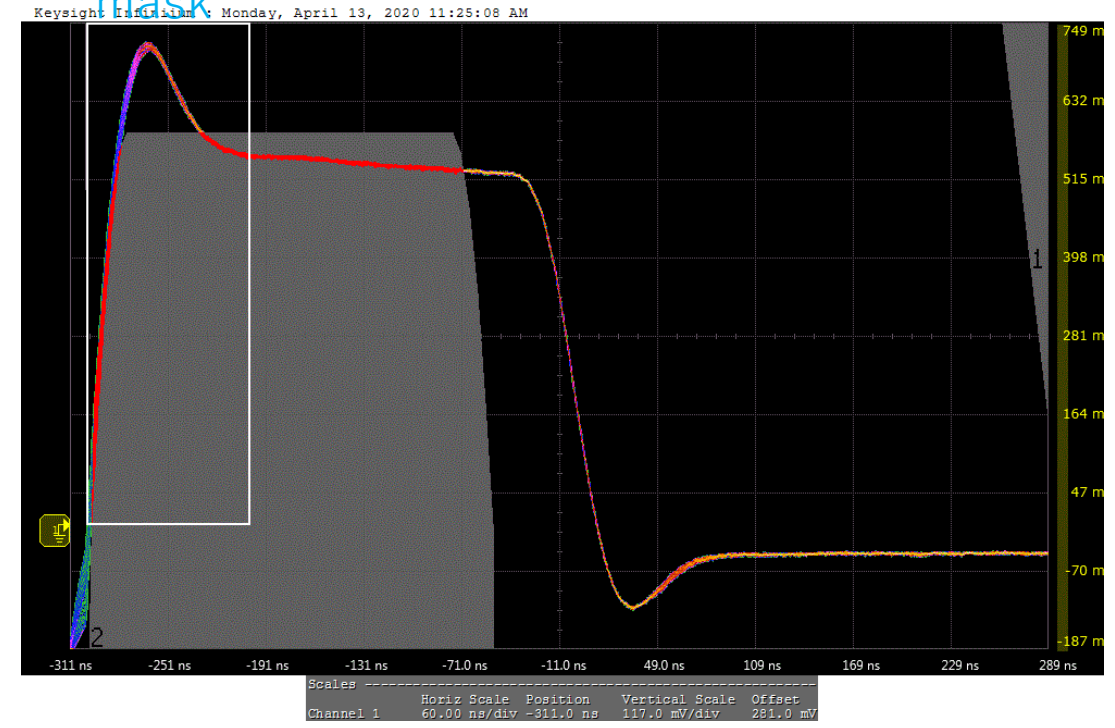
Results: 10Base-Te ~TP_IDL Template, with TPM (last bit CD0)~

| | 10Base-T (3/11) | 10Base-Te (4/13) |
|-------|-----------------|------------------|
| Load1 | OK | OK |
| Load2 | NG | NG |
| Load3 | OK | OK |

NG level: Middle
Overshoot at rising edge of signal is large



NG level: Middle
In the Load2 test, the voltage is low and hits the mask



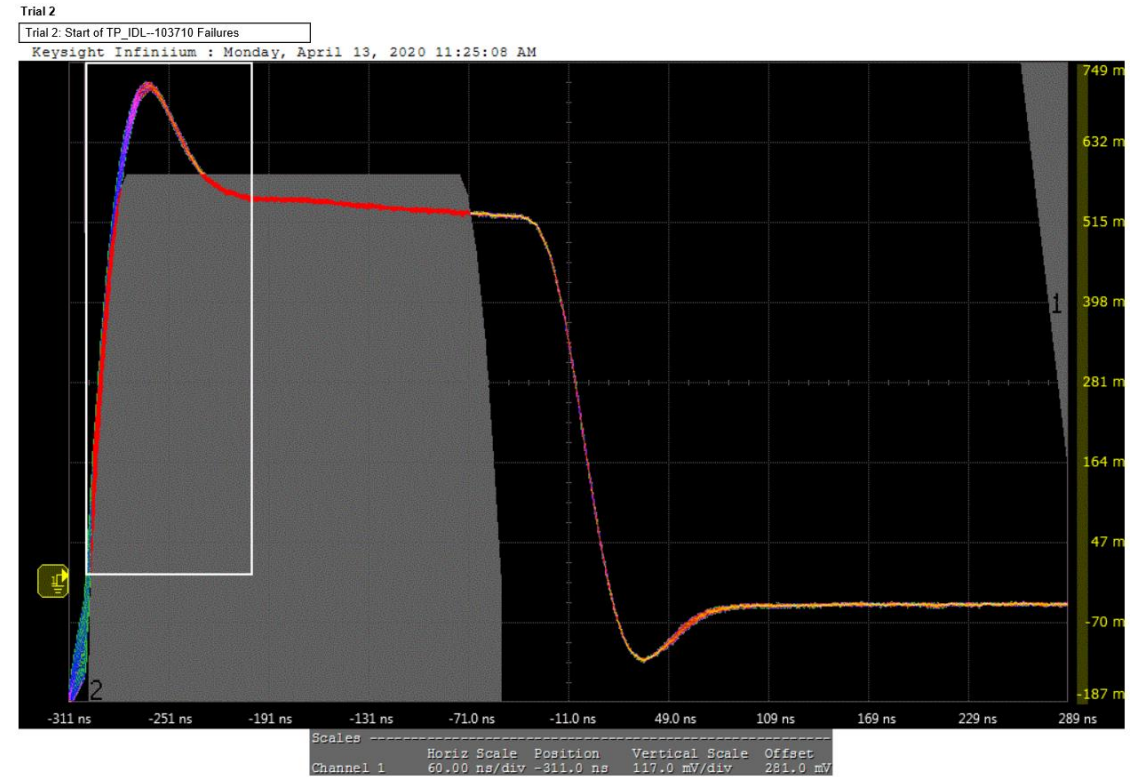
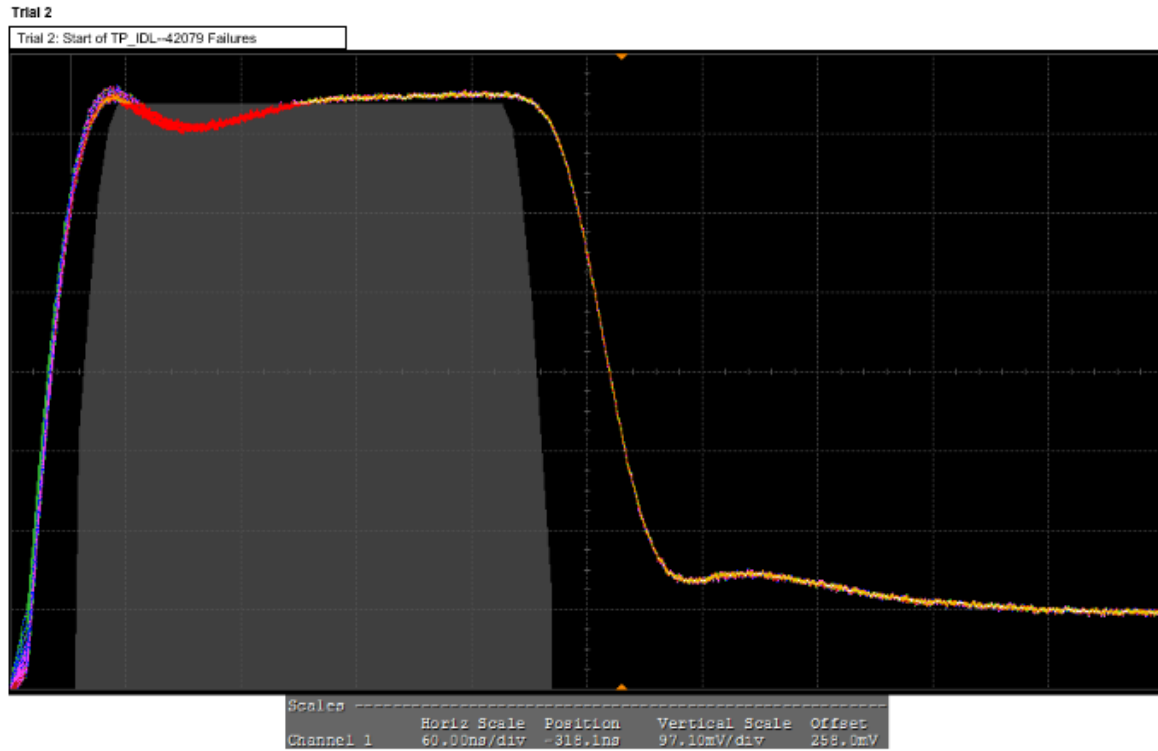
3/11試験 Load2 (基盤No3)

4/13試験 Load2 (基盤No3)

Results: 10Base-T_e ~TP_IDL Template, with TPM (last bit CD1)~

| | 10Base-T (3/11) | 10Base-T _e (4/13) |
|-------|-----------------|------------------------------|
| Load1 | OK | OK |
| Load2 | NG | NG |
| Load3 | OK | OK |

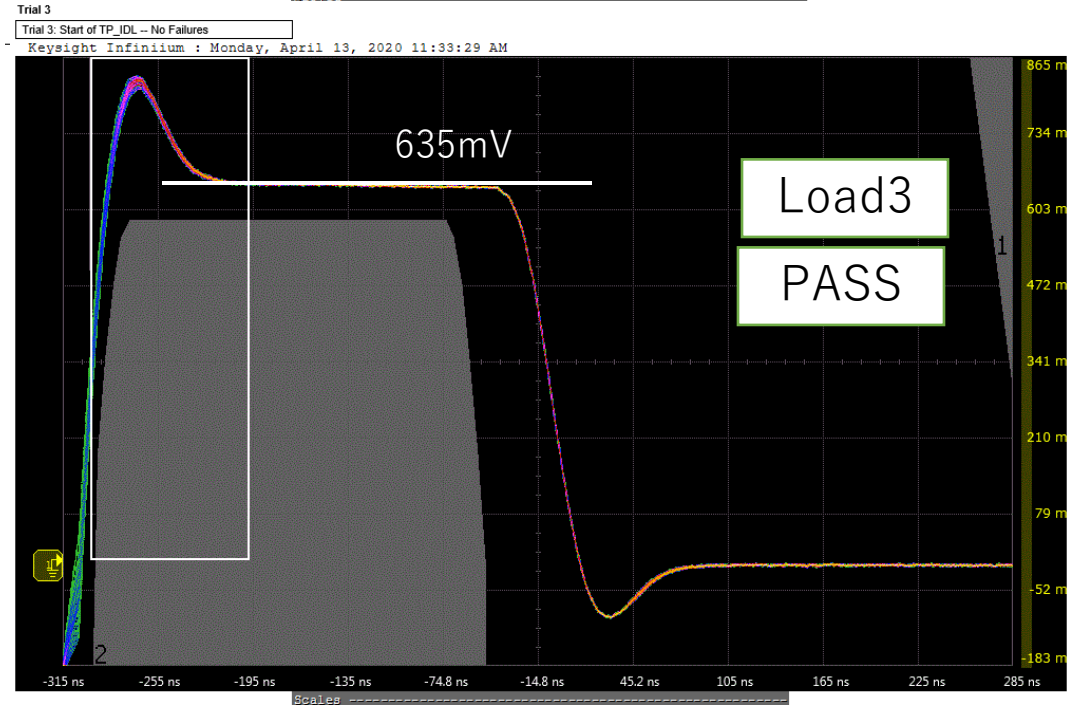
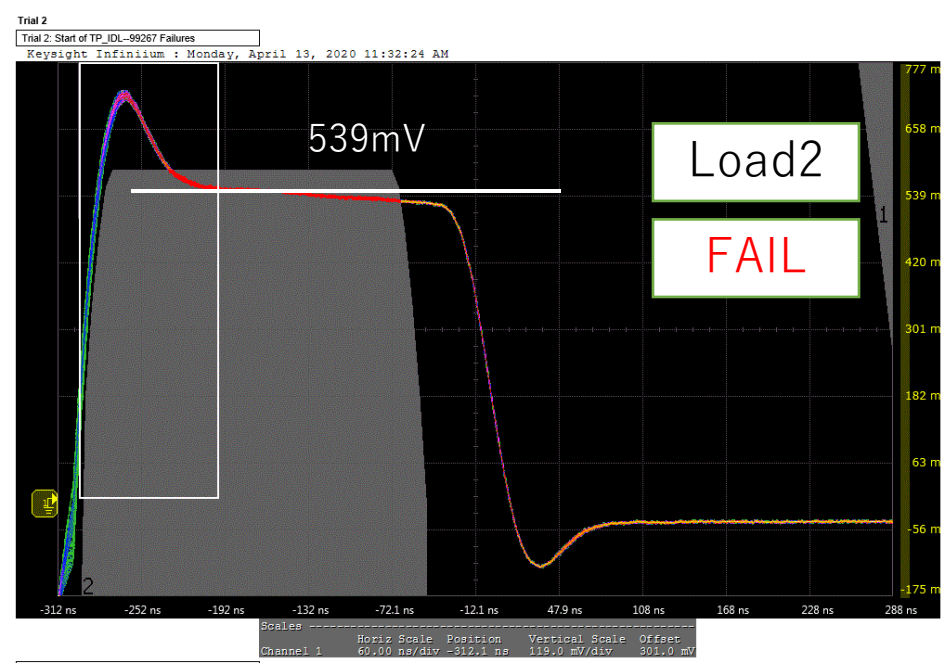
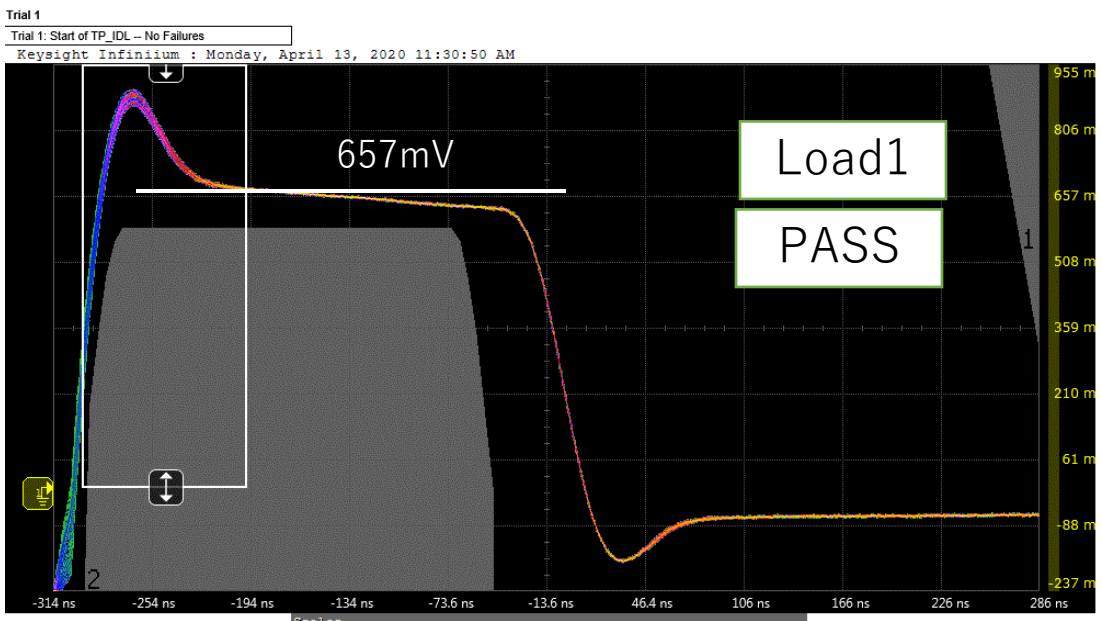
NG level: Middle
Overshoot at rising edge of signal is large



3/11試験 Load2 (基盤No3)

4/13試験 Load2 (基盤No3)

Results: 10Base-Te ~TP_IDL Template, with TPM (last bit CD1)~



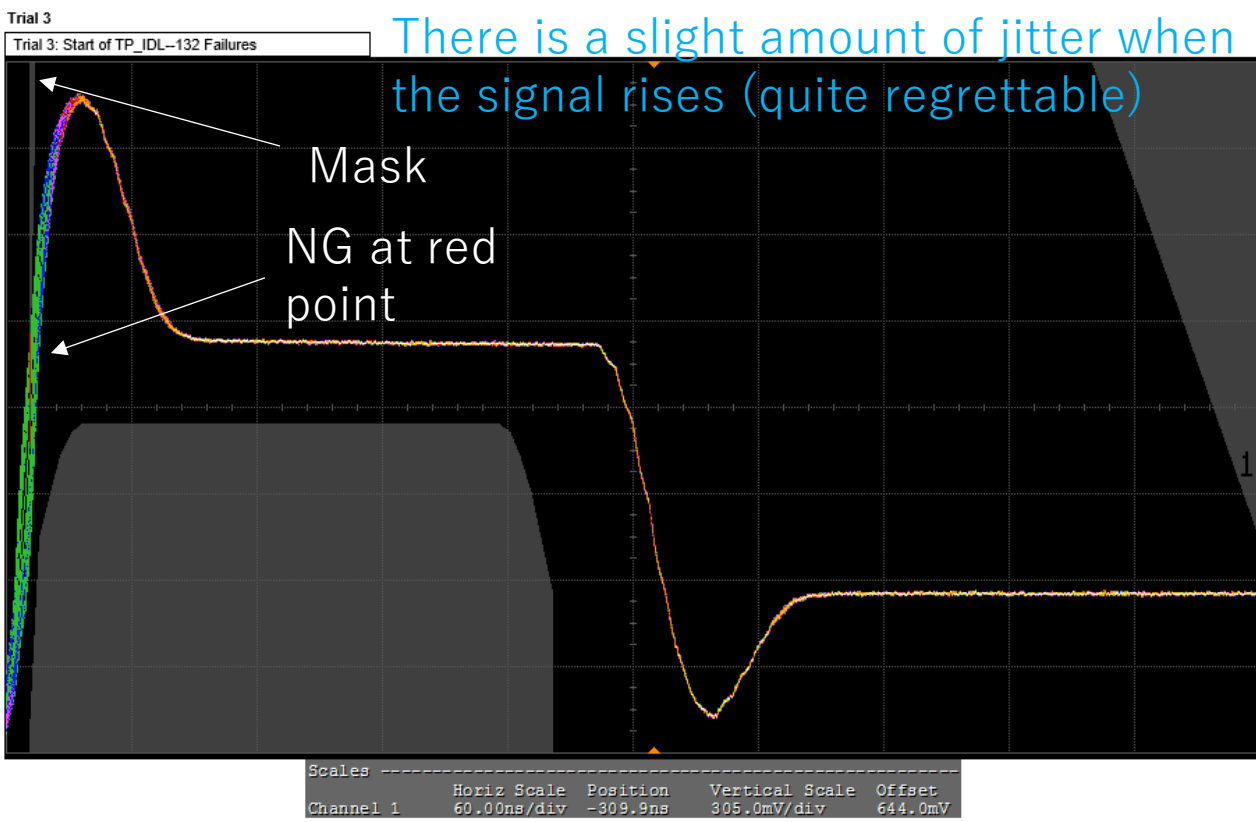
Reasons of fail at Load2:

- The mask is the same between Load1/2/3
- When calculated, the amplitude fluctuation of Load1/2/3 is almost the same as the load fluctuation ratio.
- Load1 and 3 have passed, but the upper limit of the mask is 3.1V, so the amplitude may be larger.
- Otherwise Load2 will not pass
- Need to investigate the reason more.

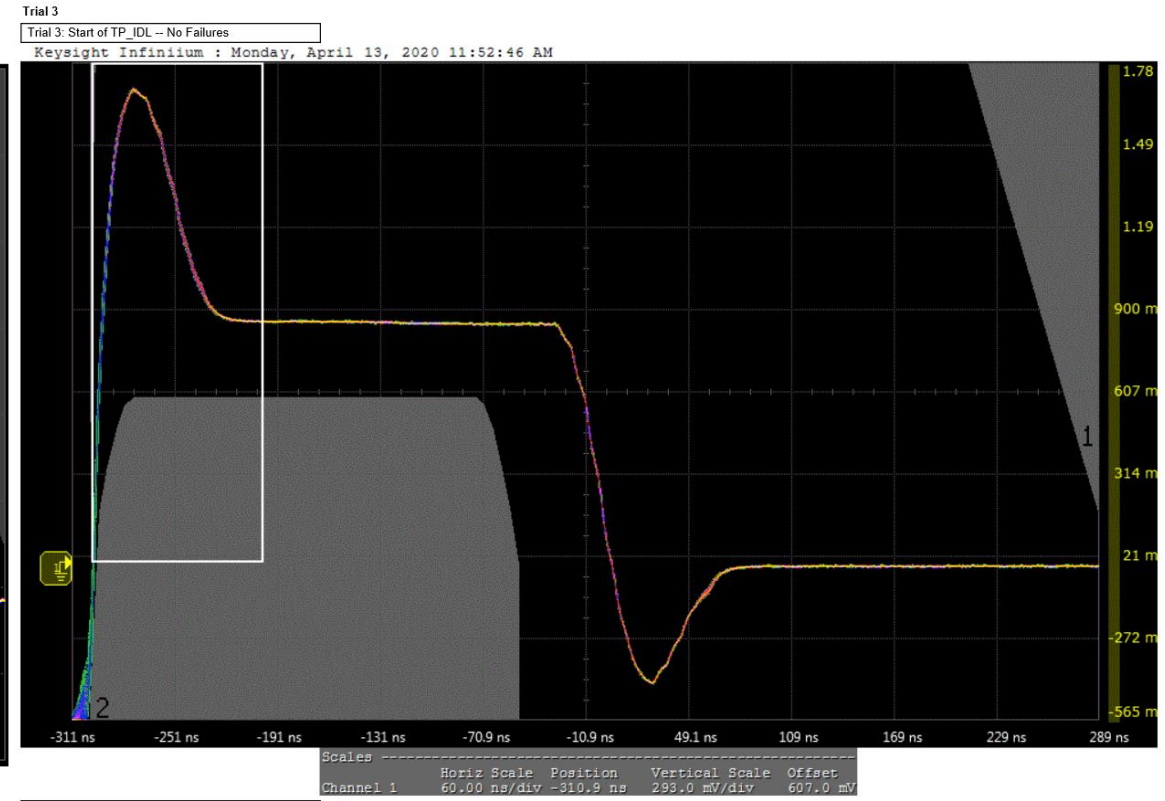
Results: 10Base-Te ~TP_IDL Template, **without** TPM (last bit CD0)~

| | 10Base-T | 10Base-Te |
|-------|----------|-----------|
| Load1 | OK | OK |
| Load2 | OK | OK |
| Load3 | NG | OK |

NG level: low
There is a slight amount of jitter when the signal rises (quite regrettable)

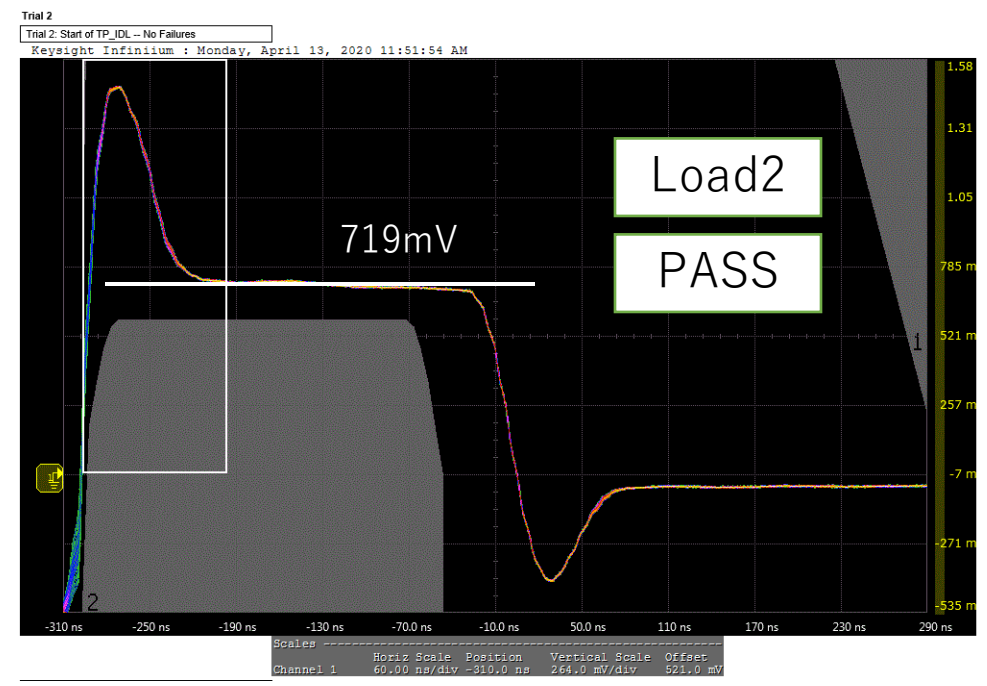
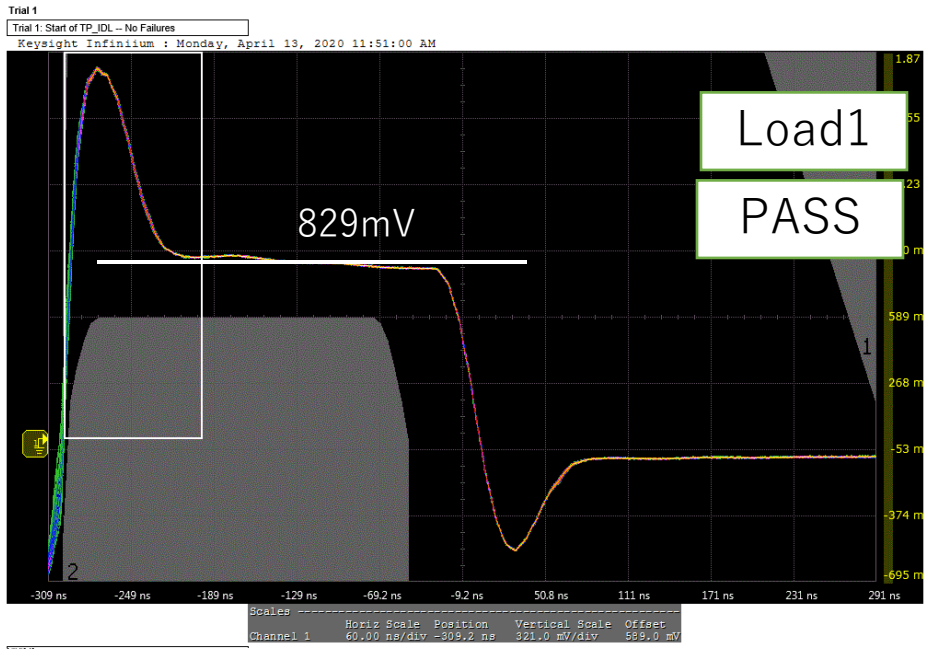


PASS

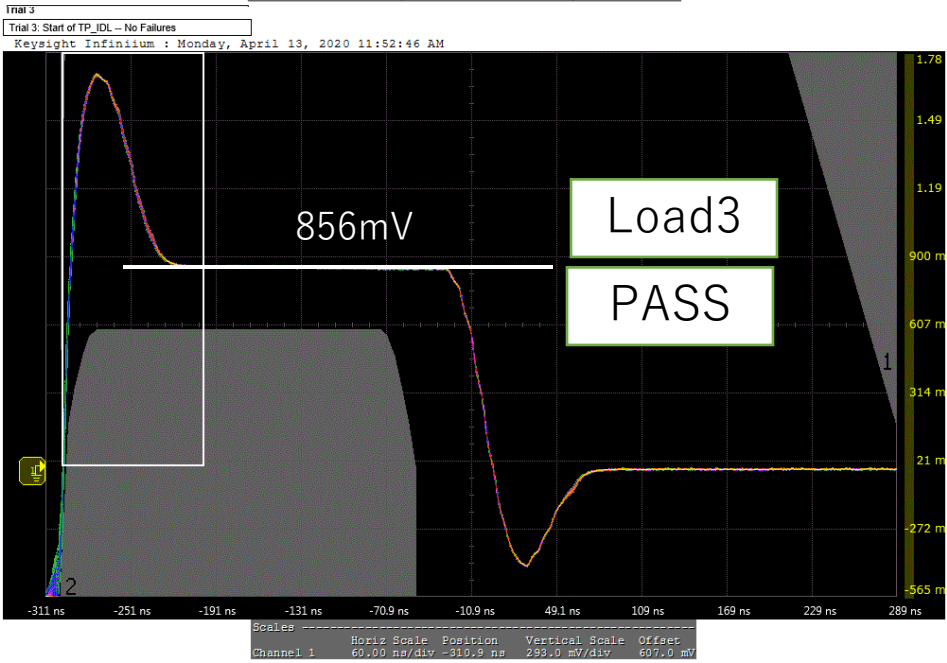


Top Drive: NEXT

Results:10Base-Te ~TP_IDL Template, without TPM (last bit CD0)~



[Empty green box]



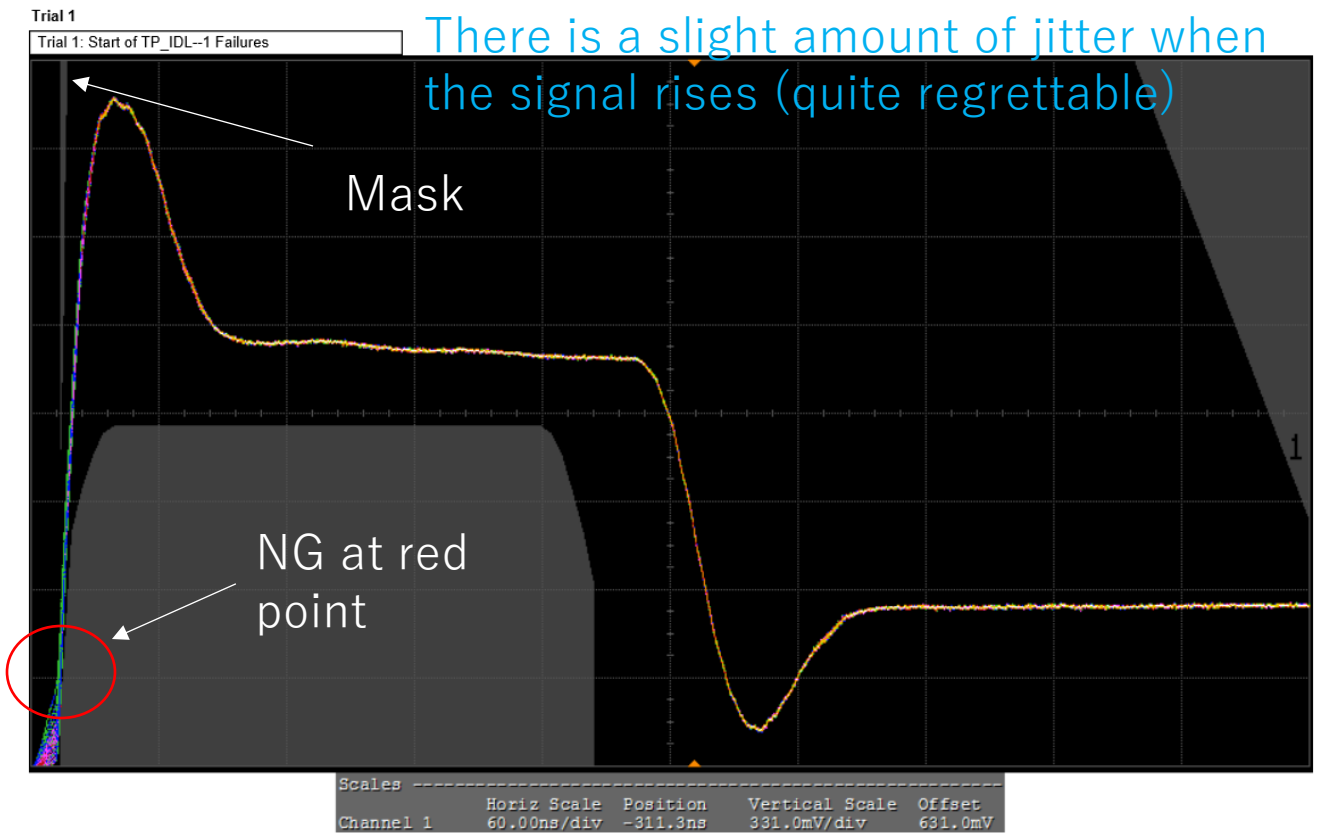
4/13試験 基盤No3)

2020.3.19
 2020.4.13
 2020.5.5

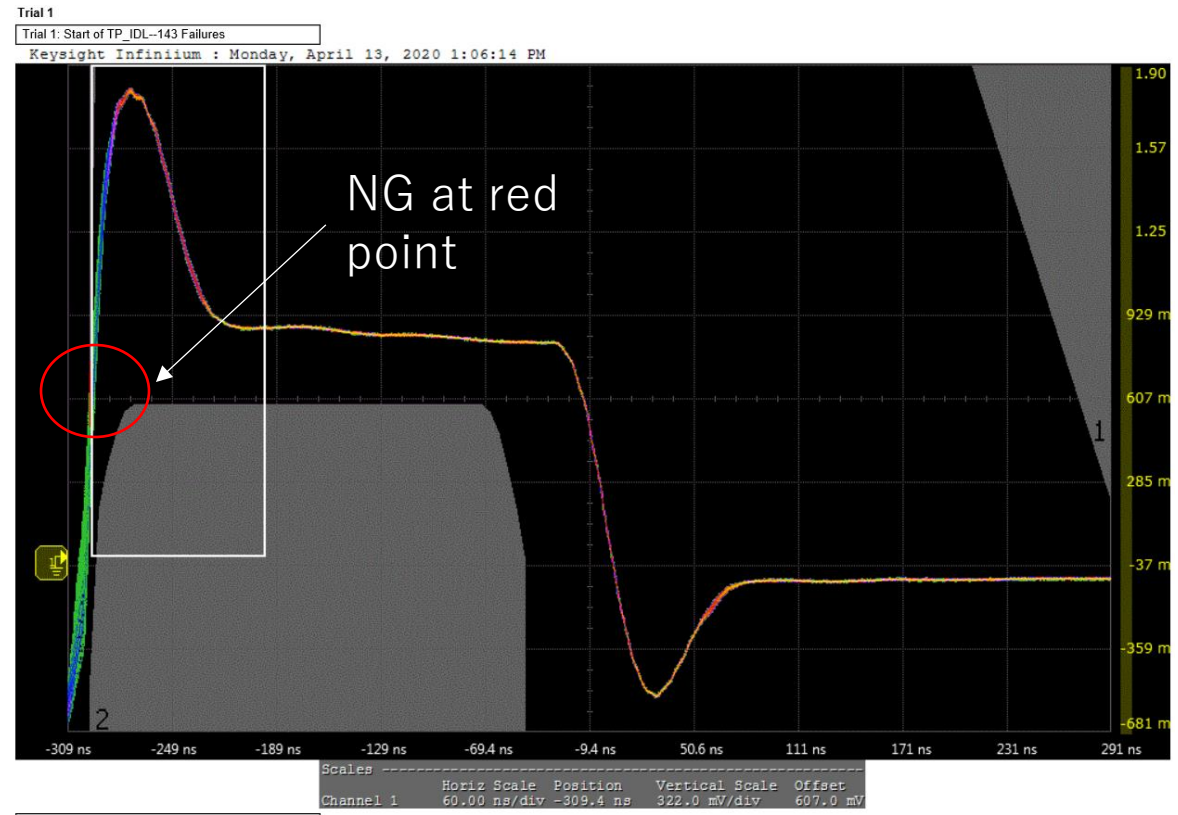
Results: 10Base-Te ~TP_IDL Template, **without** TPM (last bit CD1)~

| | 10Base-T | 10Base-Te |
|-------|----------|-----------|
| Load1 | OK | OK |
| Load2 | OK | OK |
| Load3 | NG | NG |

NG level: low
 There is a slight amount of jitter when the signal rises (quite regrettable)



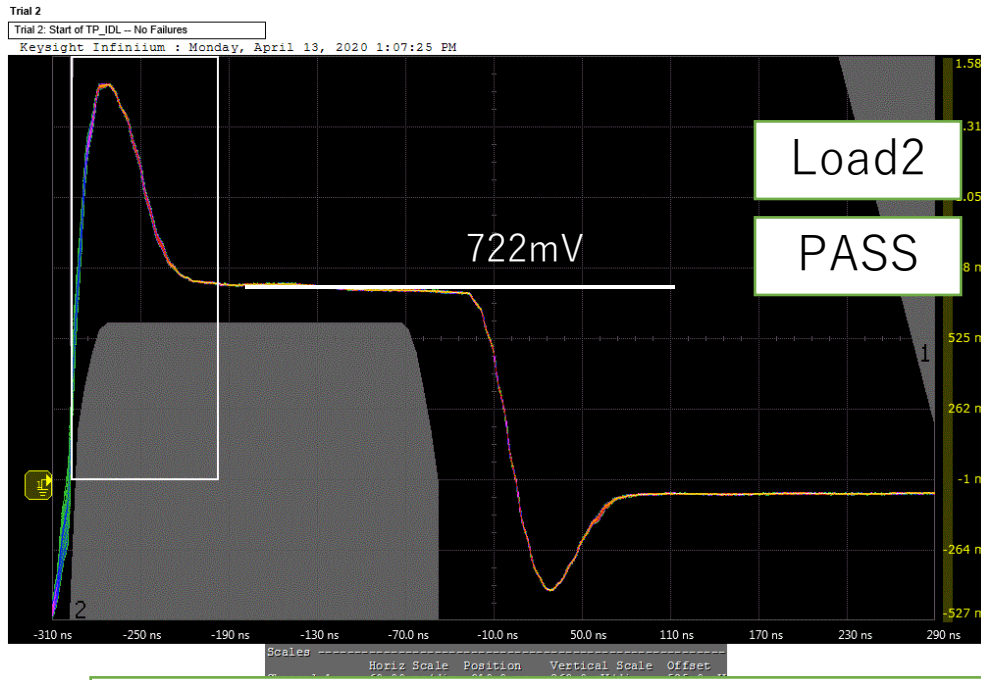
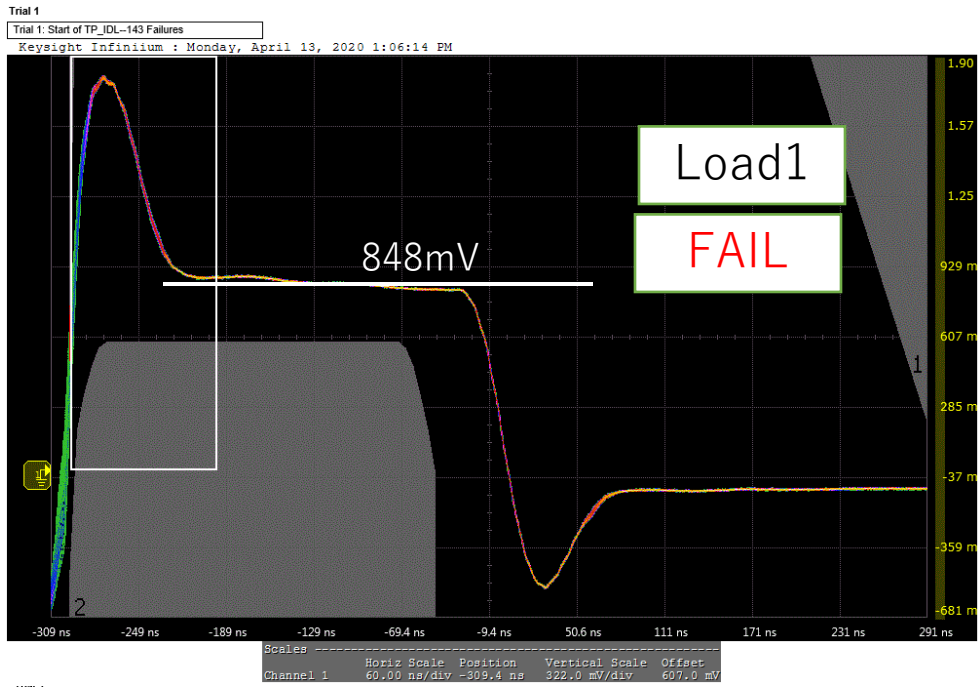
NG level: Middle
 There is jitter in the time axis direction at the rising edge of the waveform and hits the mask



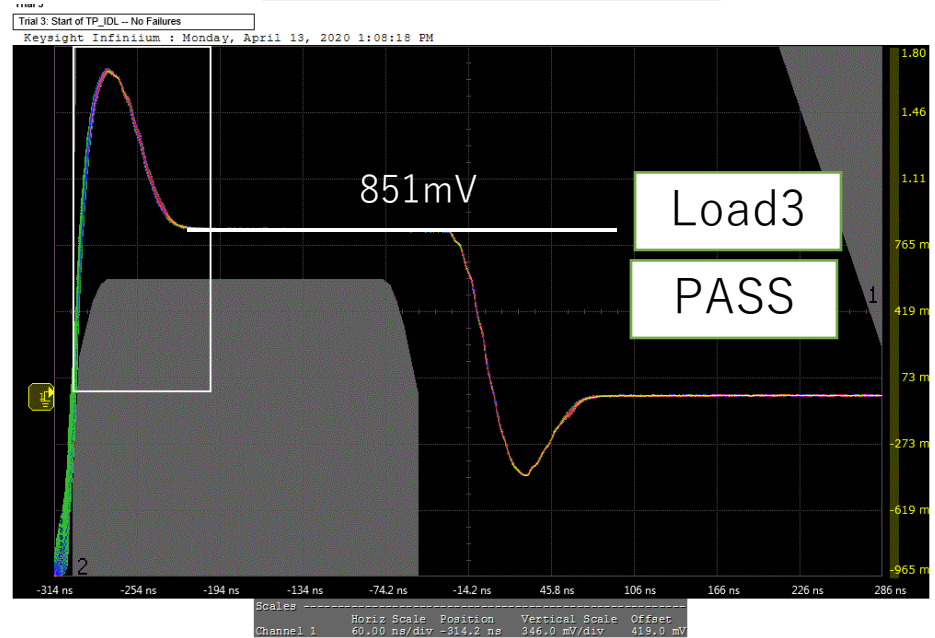
3/11試験 Load1 (基盤No3)

4/13試験 Load1 (基盤No3) 20

Results: 10Base-Te ~TP_IDL Template, *without* TPM (last bit CD1)~



[Empty green box]



4/13試験 基盤No3)

Detailed Test Results of 10Base-T:

| Items | Results | Considerations |
|--|---|--|
| TP_IDL Template, with TPM (last bit CD0) | Load1/3 : PASS Load2 : Fail Amplitude is small | Passed with Load1 / 3, Load2 does not pass unless the amplitude is larger |
| TP_IDL Template, with TPM (last bit CD1) | Same as above | Same as above |
| TP_IDL Template, without TPM (last bit CD1) | Load2/3 : PASS Load1 : Fail FAIL because the rising edge is too steep | |
| | | |
| | | |

Measurement system (10Base-T_e, TX Return loss calibration):

Section10



Section1

For RX return loss, use DB (channel B)

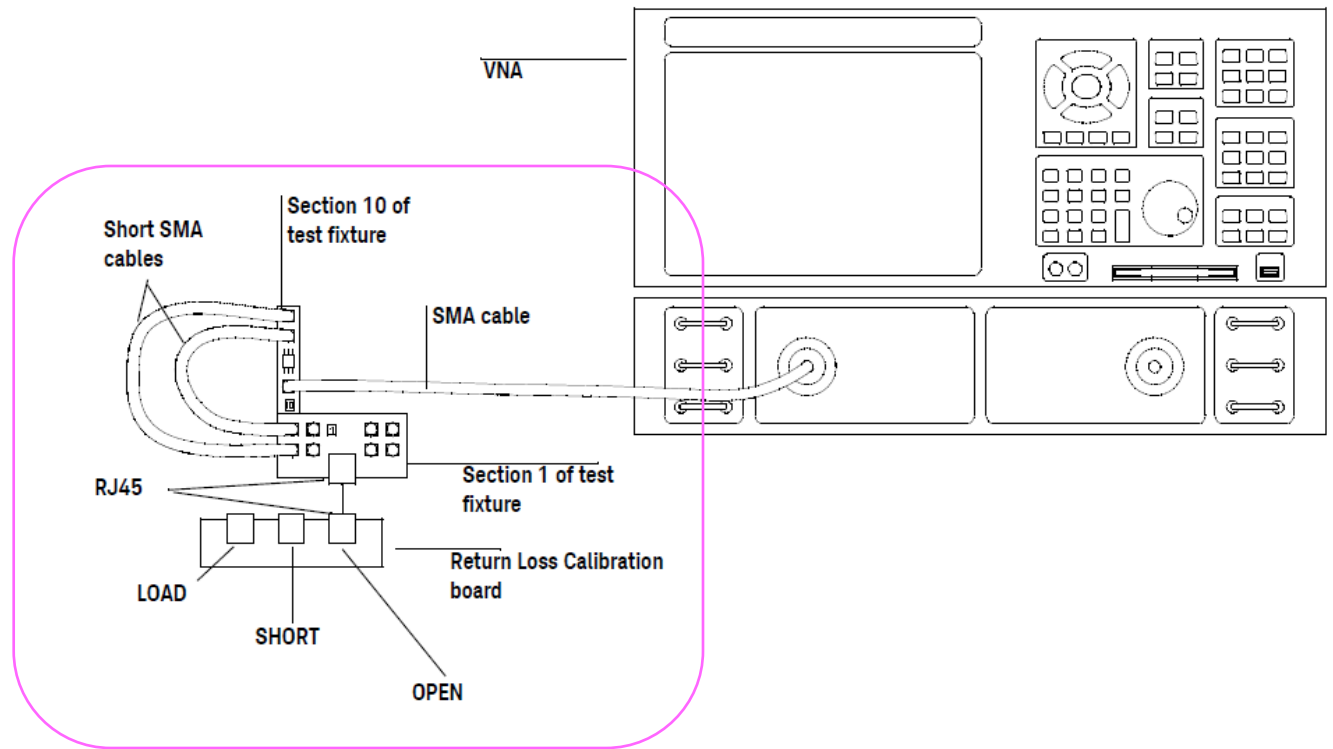
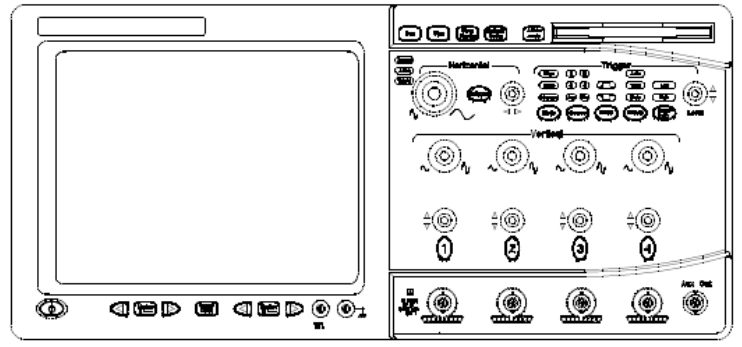


Figure 57 VNA Calibration

Measurement system (10Base-Te, Return Loss):

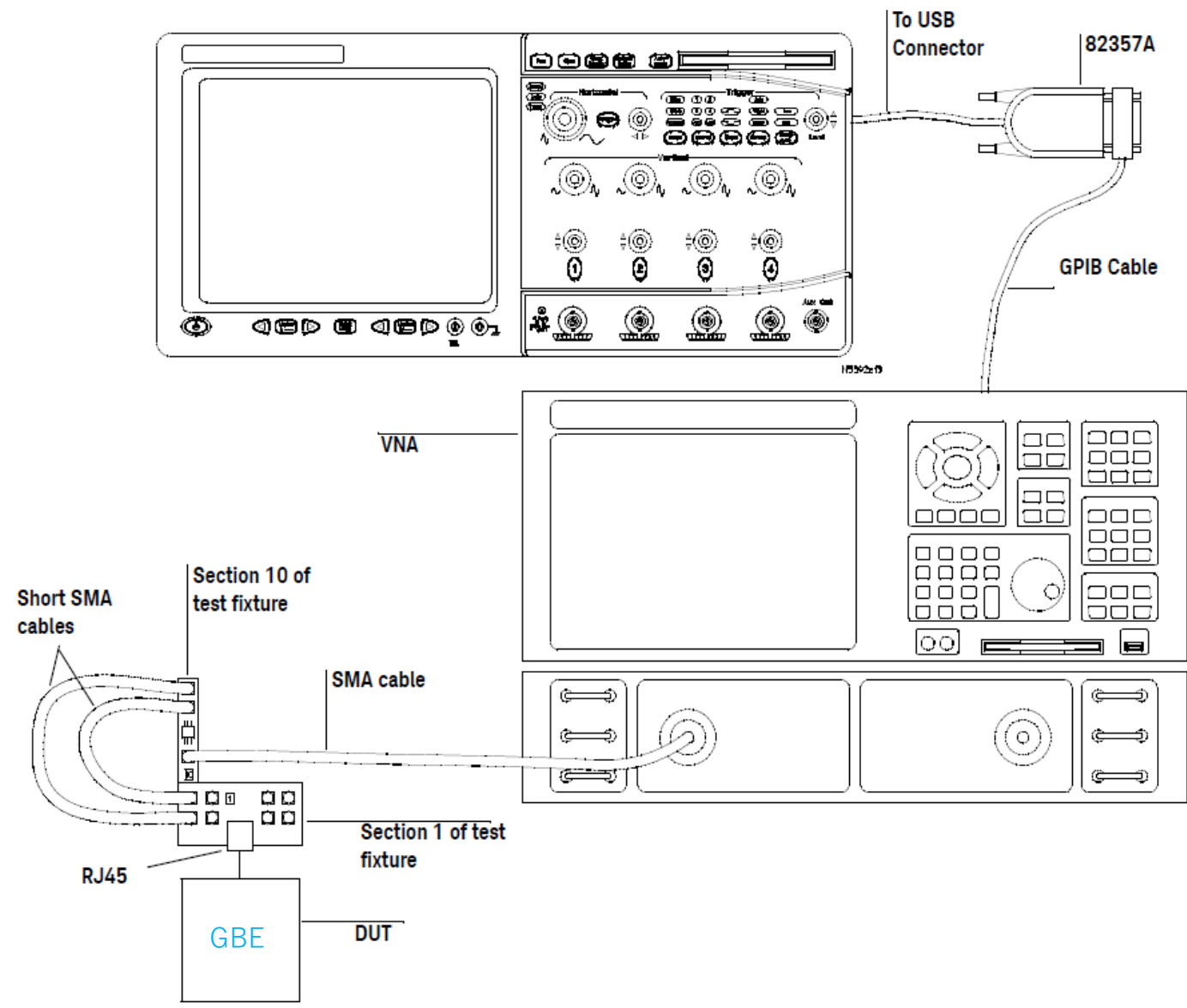


Figure 58 Probing for 10 Base-Te Transmitter Return Loss

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✘ 10 Base-T, Transmitter Return Loss

Test Summary: FAIL | Test Description: | The Return Loss obtained must conform to the requirements specified in IEEE802.3-2008 Subclause 14.3.1.2.2 and Annex B.4.3.2

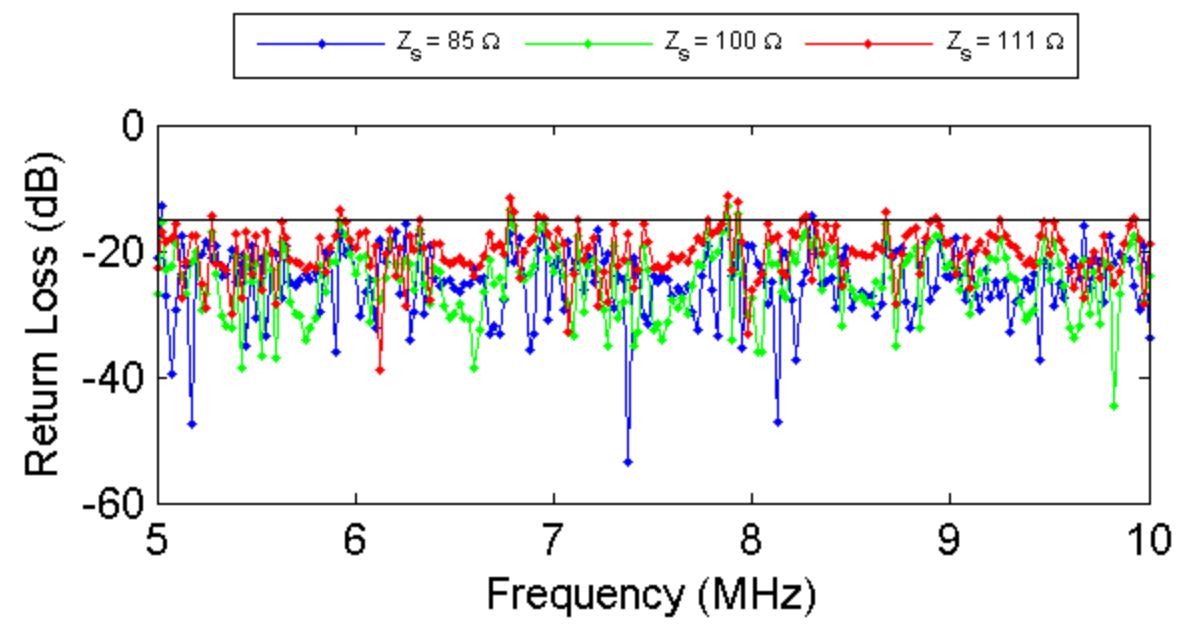
Pass Limits: > 0.00dB | Worst Margin -3.67dB

Result Details

Data File Using VNA. Return Loss vs. Frequency (See image)

Trial 1

Trial 1: Return Loss vs. Frequency

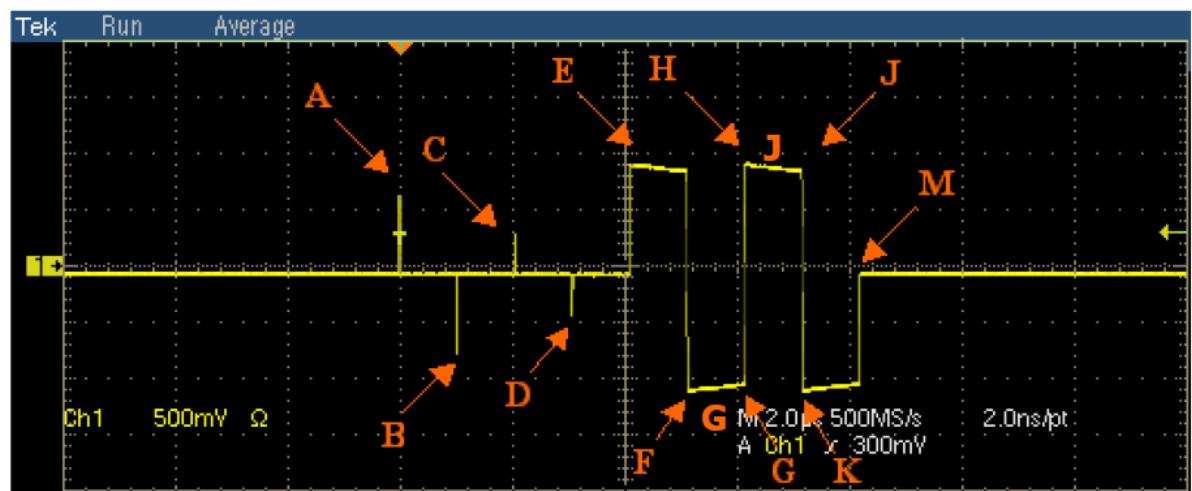


1000Base-T

Contents of Compliance Test of 1000Base-T:

Point A Peak Output Voltage(w/ Disturbing Signal)
 Point B Peak Output Voltage(w/ Disturbing Signal)
 Difference A,B Peak Output Voltage(w/ Disturbing Signal)

- ▶ Test mode 1の信号波形
- ▶ Template, Peak Voltage, Droop試験で使用
- ▶ 測定ポイントは下表の通り



| Test | Points |
|--------------|------------------------------------|
| Template | A,B,C,D,F, and H |
| Droop | G and J (上図でF またはH から500ns後ろのポイント) |
| Peak Voltage | A,B,C, and D |

Measurement system (1000Base-T):

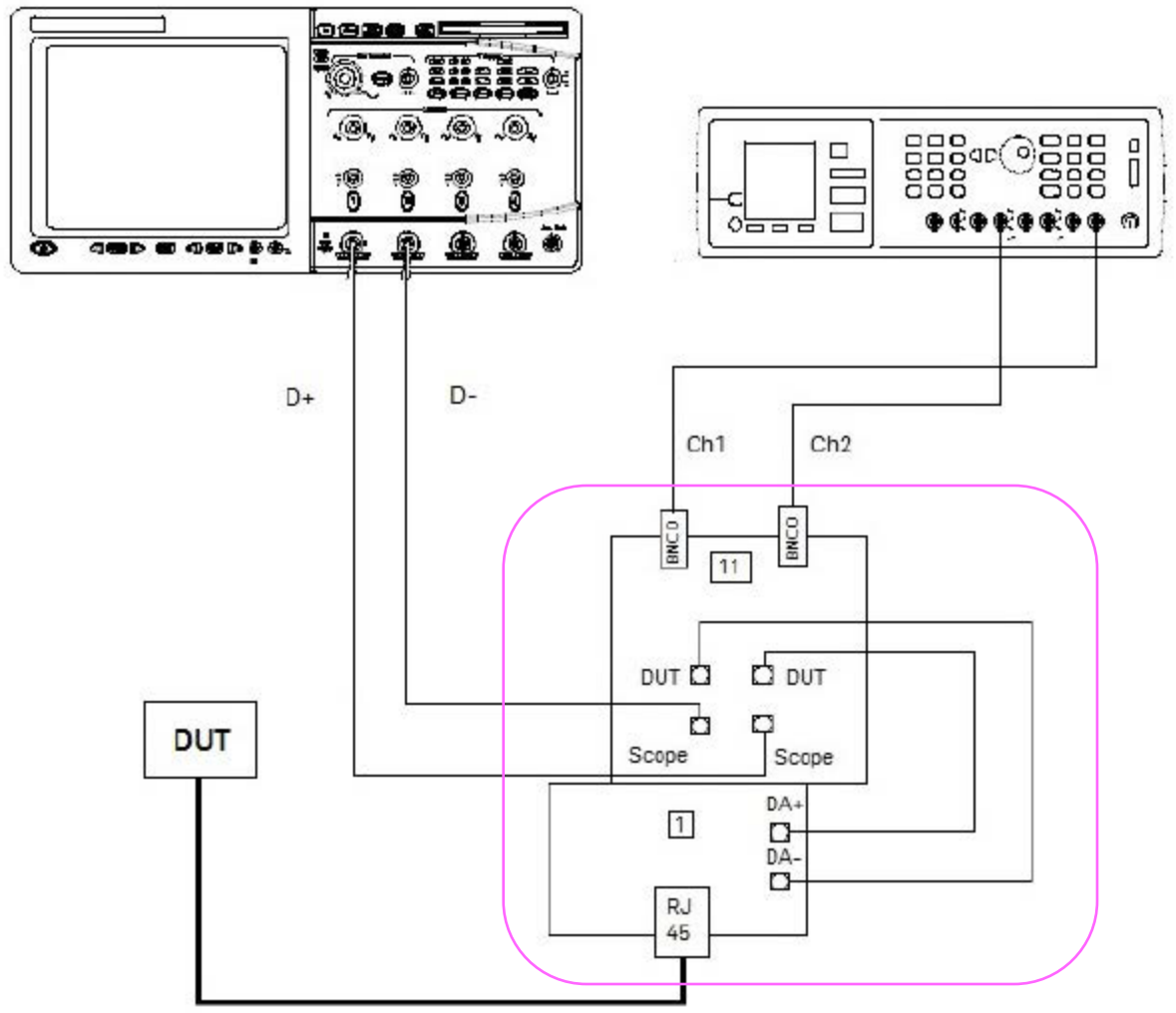
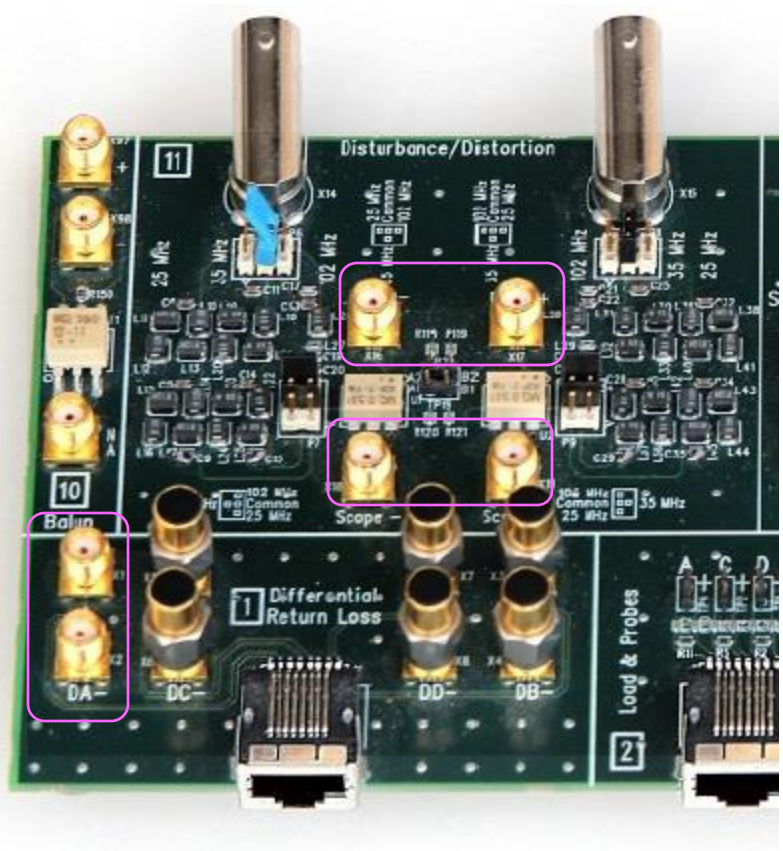
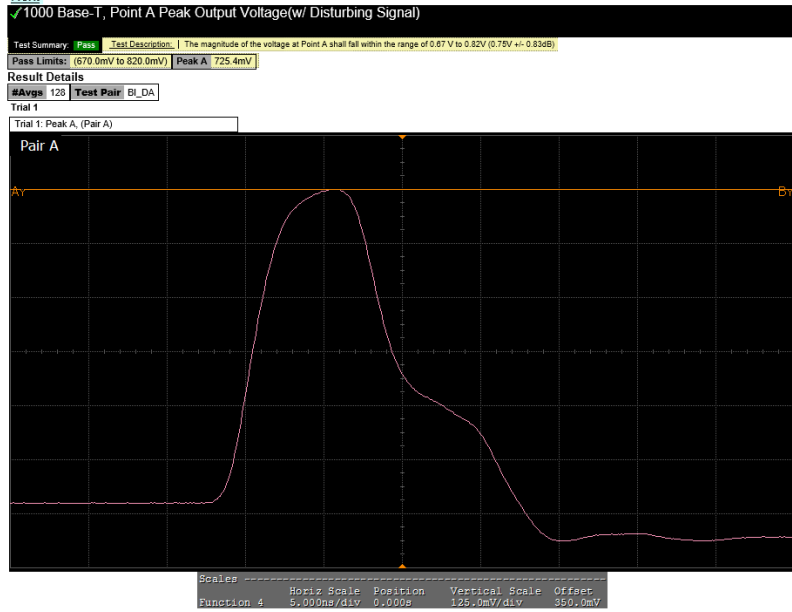


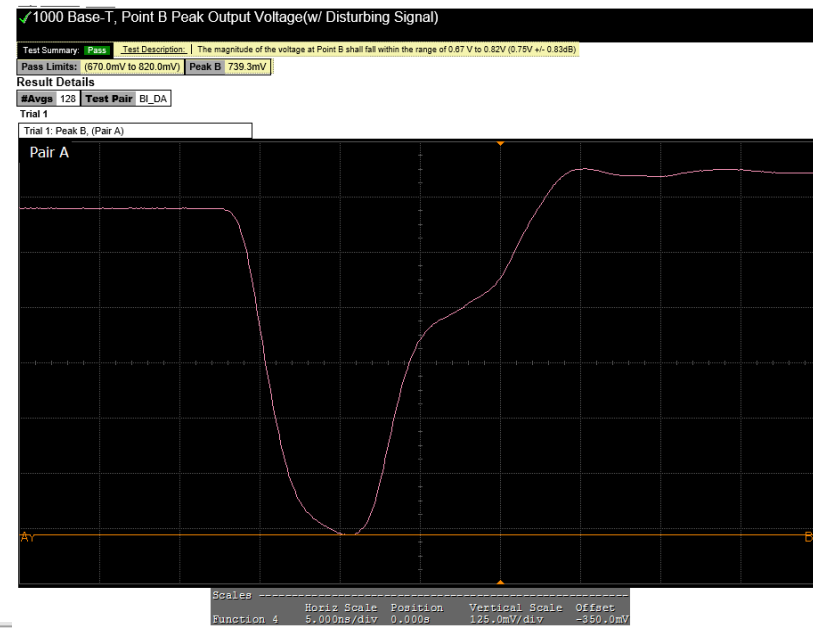
Figure 8 Probing for 1000 Base-T Test Mode 1 Tests

Results: 1000Base-T:

Point A



Point B



| Difference A,B Peak Output Voltage(w/ Disturbing Signal) | | | | | | | | | | | | | | | | | | | | |
|--|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|--------|
| No3 | | | | | | | | | | | | | | | | | | | | |
| ポート | P1 | | | | P2 | | | | P3 | | | | P4 | | | | TEST | | | |
| チャンネル | A | B | C | D | A | B | C | D | A | B | C | D | A | B | C | D | A | B | C | D |
| Peak A [mV] 670~820 mV | 725.4 | 723.7 | 717.8 | 721.6 | 727.3 | 720.1 | 722.6 | 726.5 | 734.6 | 722.7 | 733.4 | 736.9 | 738.8 | 711.3 | 721.7 | 738.4 | 726.5 | 720.1 | 721.7 | 724.3 |
| Peak B [mV] 670~820 mV | -739.3 | -723.4 | -722 | -731.5 | -741 | -727.7 | -722.9 | -732.8 | -742.4 | -731.7 | -739.2 | -743.8 | -746.9 | -716.3 | -729.8 | -747.6 | -733.3 | -716.9 | -723.1 | -730.5 |
| difference <1% | 1.90% | 0.03% | 0.59% | 1.37% | 1.86% | 1.04% | 0.05% | 0.87% | 1.05% | 1.25% | 0.78% | 0.93% | 1.10% | 0.70% | 1.11% | 1.23% | 0.93% | 0.45% | 0.20% | 0.85% |
| No4 | | | | | | | | | | | | | | | | | | | | |
| ポート | P1 | | | | P2 | | | | P3 | | | | P4 | | | | TEST | | | |
| チャンネル | A | B | C | D | A | B | C | D | A | B | C | D | A | B | C | D | A | B | C | D |
| Peak A [mV] 670~820 mV | 735.3 | 722.9 | 724.6 | 733.7 | 703.2 | 719 | 719.3 | 729.3 | 725.7 | 727.3 | 711.2 | 734.5 | 722 | 724.8 | 725.7 | 740.7 | 727.7 | 713.7 | 742.7 | 729.4 |
| Peak B [mV] 670~820 mV | -739.1 | -723.6 | -728.8 | -742.5 | -713.3 | -722.8 | -723.2 | -738.9 | -729.3 | -733 | -715.3 | -742 | -731.7 | -734.5 | -733.9 | -754.5 | -732.5 | -722.2 | -752.6 | -741.4 |
| difference <1% | 0.52% | 0.10% | 0.57% | 1.19% | 1.43% | 0.53% | 0.17% | 1.31% | 0.49% | 0.79% | 0.14% | 1.01% | 1.34% | 1.33% | 1.13% | 1.84% | 0.66% | 1.18% | 1.33% | 1.63% |

Contents of compliance test of 1000Base-T:

2020.3.11

2020.4.16

IEEE Std 802.3-2008 翻訳

40.6.1.2.1 Peak differential output voltage and level accuracy

The absolute value of the peak of the waveform at points A and B, as defined in Figure 40-19, shall fall within the range of 0.67 V to 0.82 V (0.75 V \pm 0.83 dB). These measurements are to be made for each pair while operating in test mode 1 and observing the differential signal output at the MDI using transmitter test fixture 1 with no intervening cable.

The absolute value of the peak of the waveforms at points A and B shall differ by less than 1% from the average of the absolute values of the peaks of the waveform at points A and B.

The absolute value of the peak of the waveform at points C and D as defined in Figure 40-19 shall differ by less than 2% from 0.5 times the average of the absolute values of the peaks of the waveform at points A and B.

×

40.6.1.2.1ピーク差動出力電圧とレベル精度

図40-19で定義されているポイントAおよびBでの波形のピークの絶対値は、0.67 V～0.82 V (0.75 V \pm 0.83 dB) の範囲内であればなりません。これらの測定は、テストモード1で動作し、ケーブルを介さずに送信機テストフィクスチャ1を使用してMDIで差動信号出力を観察しながら、各ペアに対して行われます。

A点とB点の波形のピークの絶対値は、A点とB点の波形のピークの絶対値の平均と1%未満の差があります。

図40-19で定義されているポイントCおよびDでの波形のピークの絶対値は、ポイントAおよびBでの波形のピークの絶対値の平均の0.5倍から2%未満の差があります

40. 6. 1. 2. 1 Pīku-sa dō shutsuryoku den'atsu to reberu seido-zu 40 - 19 de teigi sa rete iru pointo A oyobi B de no hakei no pīku no zettaichi wa, 0. 67 V ~ 0. 82 V (0 . 75 V \pm 0. 83 DB) no han'i-naidenakereba narimasen. Korera no sokutei wa, tesutomōdo 1 de dōsa shi,

1000Base-T Test Mode 1 standard:

Difference between Point A and B did not become within standard

測定器の使用

Keysight D9010ETHC
Ethernet Compliance Test
Application

Table 15 Allowable Ranges for Peak Output Voltage Measurements

| Point on Test Mode 1 Signal | Allowable Range | Description |
|-----------------------------|--|--|
| Point A | 0.67 V to 0.82 V | Absolute value of Peak A is 0.75 V +/- 0.83 dB |
| Point B | Peak B between 0.67 V and 0.82 V | Absolute value of Peak B is 0.75 V +/- 0.83 dB |
| Difference A,B | $100 * \left[\frac{(\text{Peak B} - \frac{1}{2} * (\text{Peak A} + \text{Peak B}))}{(\frac{1}{2} * (\text{Peak A} + \text{Peak B}))} \right]$ | Absolute values of amplitude of Peaks A and B differ by less than 1% ^[1] |
| Point C | $< 2\% \text{ of } \frac{1}{2} * (\text{Peak A} + \text{Peak B}) / 2$ | Absolute value of Peak C is within 2% of $\frac{1}{2}$ the average amplitude of Peaks A and B ^[1] |
| Point D | $< 2\% \text{ of } \frac{1}{2} * (\text{Peak A} + \text{Peak B}) / 2$ | Absolute value of Peak D is within 2% of $\frac{1}{2}$ the average amplitude of Peaks A and B ^[1] |

Absolute value of amplitude of Peaks A and B differ by less than 1%

^[1] NOTE: The specified tolerance for this measurement is extremely tight. If this test fails, consult the vertical gain accuracy of your oscilloscope before you draw any conclusions about conformance.

Results: 1000Base-T ~ Difference A,B Peak Output Voltage(w/ Disturbing Signal):

2020.3.19

2020.5.5

Results of prior test (2020/3/19)

Pair B

NG level : Middle

Difference A,B peak output voltage is larger as 1.5~2% for less than 1%

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✖ 1000 Base-T, Difference A,B Peak Output Voltage(w/ Disturbing Signal)

Test Summary: **FAIL** Test Description: | The absolute value of the peak of the waveform at points A and B shall differ by less than 1%

Pass Limits: < 1.00% % Difference 1.90%

Result Details

| | | | | | | | |
|--------------|---------|--------------|----------|------|-----|-----------|-------|
| Peak A Volts | 725.4mV | Peak B Volts | -739.3mV | #Avg | 128 | Test Pair | BI_DA |
|--------------|---------|--------------|----------|------|-----|-----------|-------|

Calculation results do not match measurement results
Calculation result is about half of measurement result
Is the formula wrong?

Formula: $100 * [(|Peak B| - \frac{1}{2} * (|Peak A| + |Peak B|)) / (\frac{1}{2} * (|Peak A| + |Peak B|))]$

* If numerator of “ $\frac{1}{2} * (|Peak A| + |Peak B|)$ ” was “|Peak A|”, calculation results would match measurement results



They wondered if they didn't match, but they found that the measurement result and the calculation formula matched.
See next page (2020.5.5)

1000Base-T Test Mode 1 standard:

The level difference between Point A and B does not meet the standard

Understand the measurement contents from the specifications of IEEE802.3 and the specifications of the measuring instrument (calculation formula)

Since the measurement result and the calculation result matched, they could understand the measurement content

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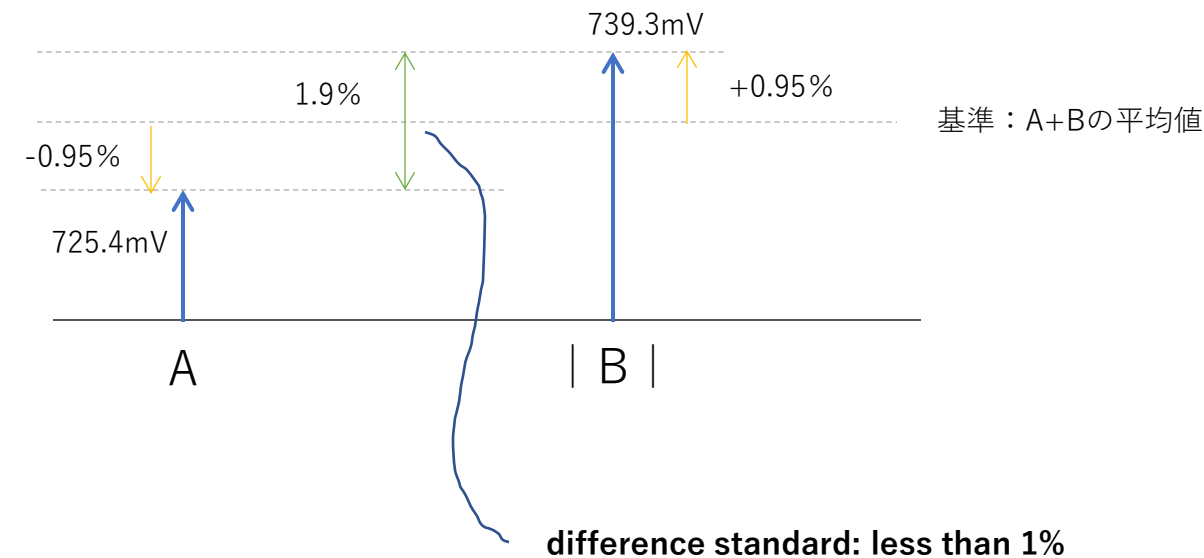
✖ 1000 Base-T, Difference A,B Peak Output Voltage(w/ Disturbing Signal)

Test Summary: **FAIL** Test Description: The absolute value of the peak of the waveform at points A and B shall differ by less than 1%

Pass Limits: < 1.00% % Difference 1.90%

Result Details

| | | | | | | | |
|--------------|---------|--------------|----------|------|-----|-----------|-------|
| Peak A Volts | 725.4mV | Peak B Volts | -739.3mV | #Avs | 128 | Test Pair | BI_DA |
|--------------|---------|--------------|----------|------|-----|-----------|-------|



| Difference A,B Peak Output Voltage(w/ Disturbing Signal) | |
|--|-------------------|
| 基盤 | |
| ポート | |
| チャンネル | A |
| Peak A [mV] | 670~820 mV 725.4 |
| Peak B [mV] | 670~820 mV -739.3 |
| difference <1% | 1.90% |
| ①計算値 Peak A 精度 | -0.95% |
| ②計算値 Peak B 精度 | 0.95% |
| ③計算値 differ = abs(①-②) | 1.90% |

Test fixture of 10Base-T is the same as that of 10Base-Te?

概要

N5392Aイーサネット電気性能検証/コンプライアンス・ソフトウェアは、Infiniiumシリーズ・オシロスコープ用のソフトウェアで、1000BASE-T、100BASE-TX、10BASE-Tイーサネット・デザインの容易な検証/デバッグを実現します。イーサネット・テスト・ソフトウェアを使用すれば、イーサネット物理層 (PHY) 電気テストを自動的に実行できます。また、テスト結果が柔軟なレポート・フォーマットで表示されます。レポートには、測定データのほかに、どの程度のマージンでデバイスが各テストに合格/不合格したかを示すマージン解析も含まれています。

イーサネット電気性能検証/コンプライアンス・ソフトウェアは、IEEE 802.3-2005およびANSI X3.263-1995規格の1000BASE-T/100BASE-TX/10BASE-Tシステム用イーサネット電気仕様に適合するさまざまなテストを提供します。

N5392Aイーサネット電気性能検証/コンプライアンス・ソフトウェアには、Keysight N5395Bイーサネット電気コンプライアンス・テスト・フィクスチャ、最低1個のInfiniiMaxアクティブ差動プローブ (1131A/1132A/1134A/1168A/1169A) およびE2678Aソケット付き差動プローブ・ヘッド、BNCケーブル (1000BASE-Tおよび10BASE-T測定の場合のみ) が必要です。1000BASE-Tのジッタ測定には、N5396Aギガビット・イーサネット・ジッタ・テスト・ケーブルとN5395Bイーサネット・テスト・フィクスチャ、2個のInfiniiMaxアクティブ差動プローブ、2個のE2677AまたはN5381Aソルダイン差動プローブ・ヘッドが必要です。

N5392Aイーサネット電気性能検証/コンプライアンス・ソフトウェアは、Microsoft Windows XP Proオペレーティング・システム搭載のすべてのInfiniiumシリーズ・オシロスコープで実行できます。

概要

N5392B Energy Efficient Ethernet電気性能検証/コンプライアンス・ソフトウェアは、Infiniiumシリーズ オシロスコープ用のソフトウェアで、1000BASE-T/100BASE-TX/10BASE-Te Energy Efficient Ethernetデザインの容易な検証/デバッグを実現します。イーサネット・テスト・ソフトウェアを使用すれば、イーサネット物理層 (PHY) 電気テストを自動的に実行できます。また、テスト結果が柔軟なレポート・フォーマットで表示されます。レポートには、測定データのほかに、どの程度のマージンでデバイスが各テストに合格/不合格になったかを示すマージン解析も含まれています。

Energy Efficient Ethernet電気性能検証/コンプライアンス・ソフトウェアは、IEEE 802.3az-2010規格の1000BASE-T/100BASE-TX/10BASE-TeシステムのEnergy Efficient Ethernet電気仕様に適合するさまざまなテストを提供します。

N5392B Energy Efficient Ethernet電気性能検証/コンプライアンス・ソフトウェアには、Wilder TechnologiesのEnergy Efficient Ethernet電気コンプライアンス・テスト・フィクスチャ (EEE-TPA-ERK)、最低1個のInfiniiMaxアクティブ差動プローブ (1131A/1132A/1134A/1168A/1169A) およびE2678Aソケット付き差動プローブ・ヘッド、SMAケーブル2本 (1000BASE-T測定の場合のみ) が必要です。

1000BASE-Tの標準イーサネット・ジッタ測定には、N5395C イーサネット・テスト・フィクスチャとN5396A ギガビット・イーサネット・ジッタ・テスト・ケーブル、2本目のInfiniiMaxアクティブ差動プローブ、2個のE2677A/N5381A はんだ付け差動プローブ・ヘッド、BNCケーブル (1000BASE-T/10BASE-Te測定の場合のみ) が必要です。

N5392Bイーサネット電気性能検証/コンプライアンス・ソフトウェアは、すべてのInfiniiumシリーズ オシロスコープで動作します。

